

Week 10

Light emitters 3

Outcoupling Strategies
Reliability

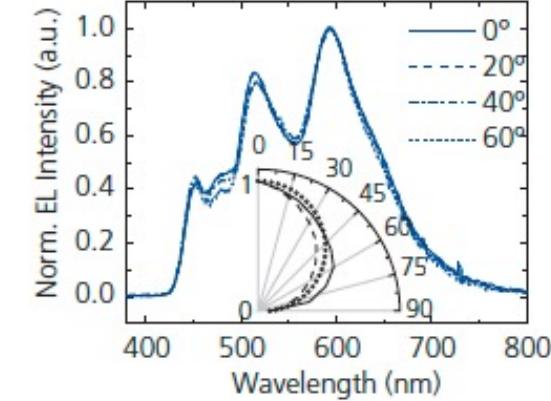
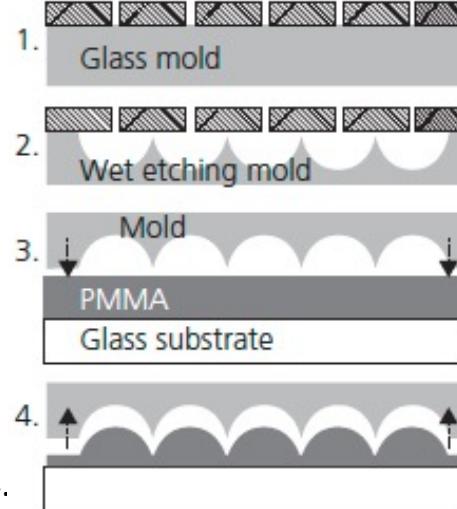
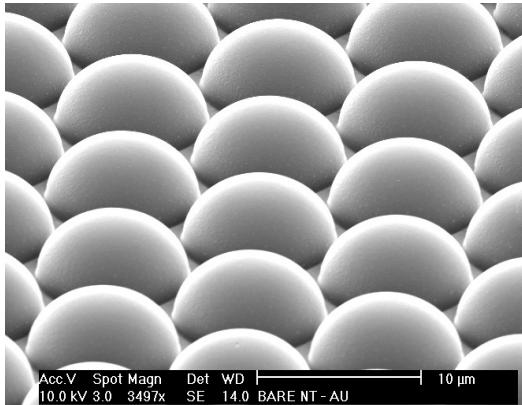
Chapter 6.6.2-6.7

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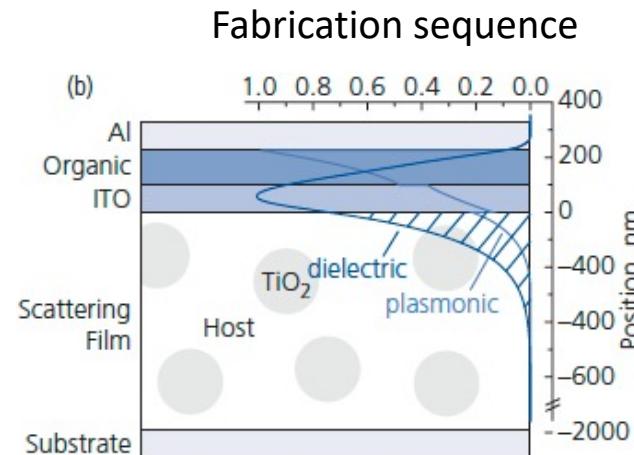
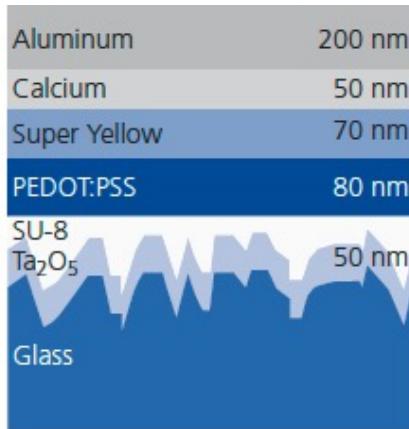
Substrate Mode Outcoupling: $\sim 2X$ Improvement

$\eta_{ext} \sim 40\%$

Microlens arrays: Polymer hemispheres much smaller than pixel



Möller, S. & Forrest, S. R. 2001. *J. Appl. Phys.*, 91, 3324.



Spectrum angle independent

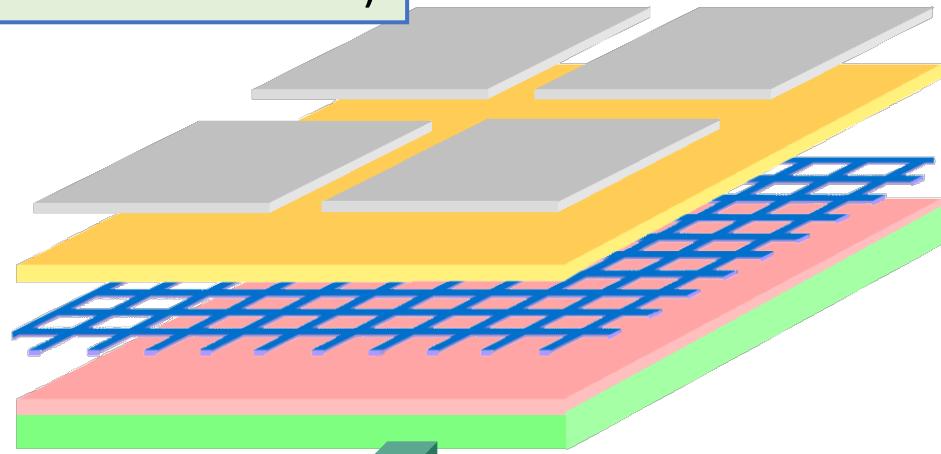
⇒ Scattering and surface roughness also can reduce substrate modes



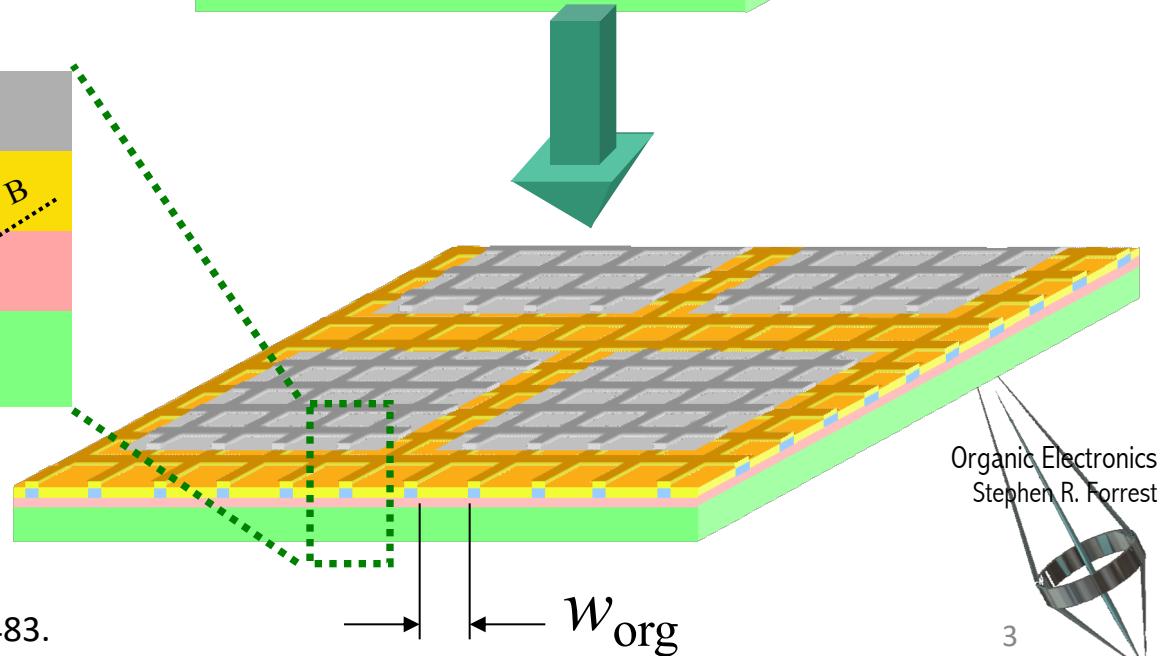
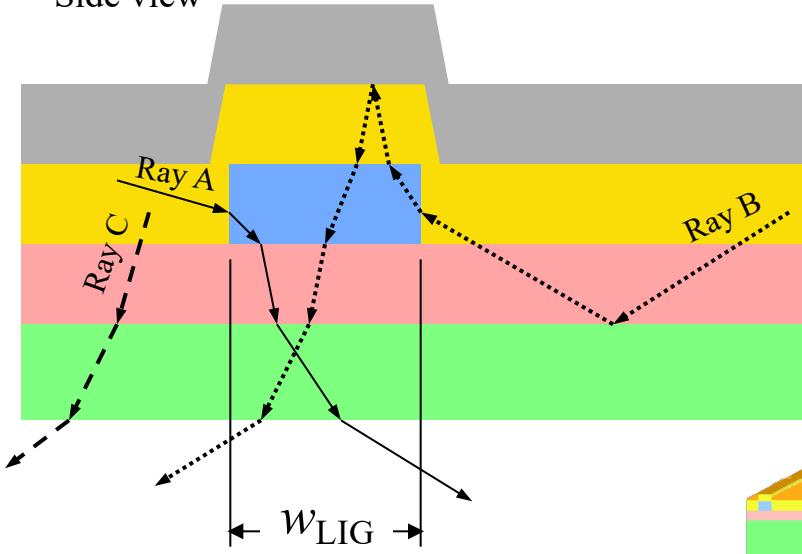
Waveguide Mode Outcoupling: Embedded Low Index Grid

- Metal electrode pixel
- Organics
- Low-index grid
- ITO
- Glass substrate

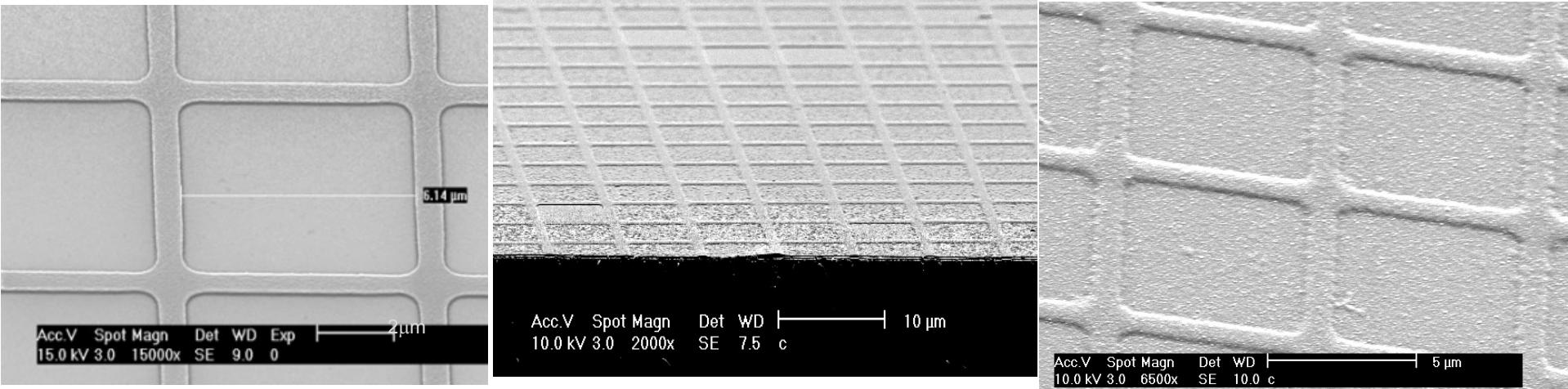
$\eta_{\text{ext}} \sim 60\% \text{ (incl. substrate modes)}$



Side view

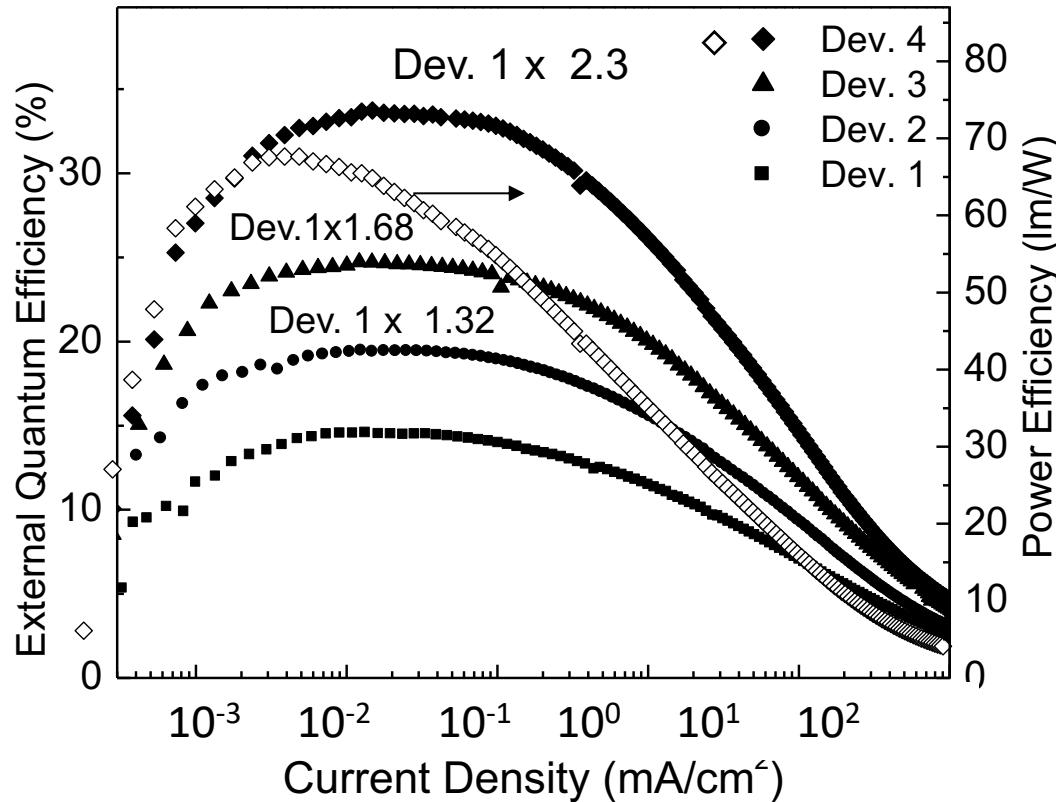


Low Index Grid Images

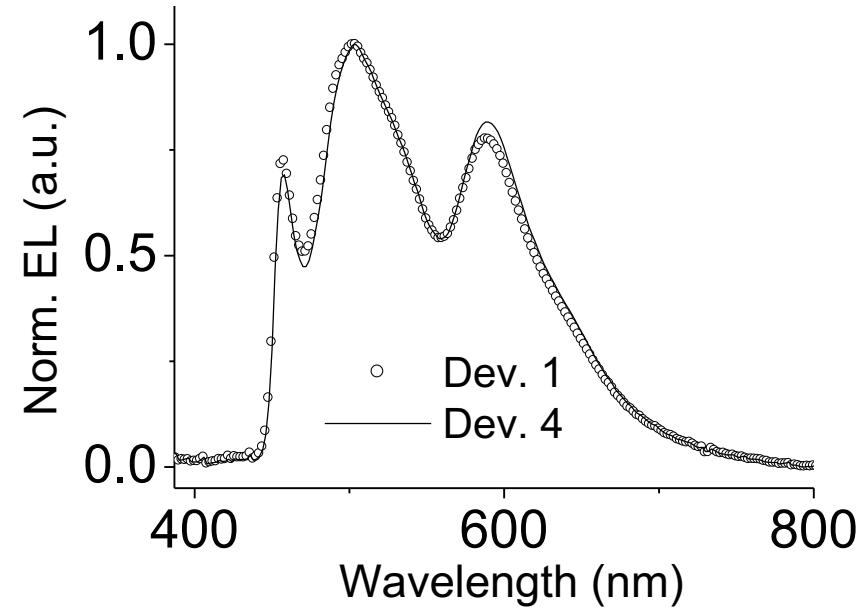


- OLED >> Grid size >> Wavelength
- Embedded into OLED structure
- May partially decouple waveguide mode from SPPs

Hybrid WOLED Performance Using Embedded Grids + Microlens Arrays



Device 1: Conventional
Device 2: LIG only
Device 3: Microlenses only
Device 4: LIG + Microlenses

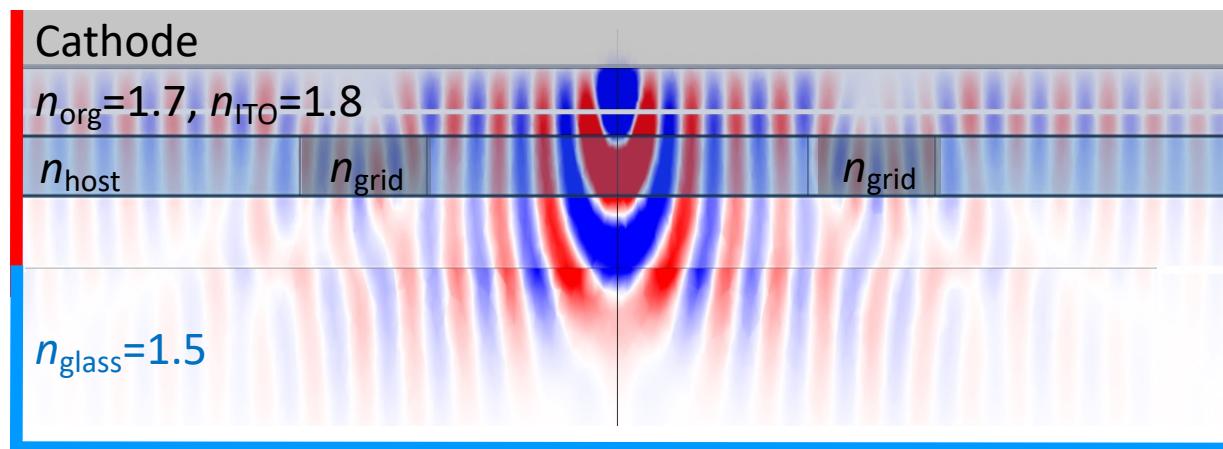
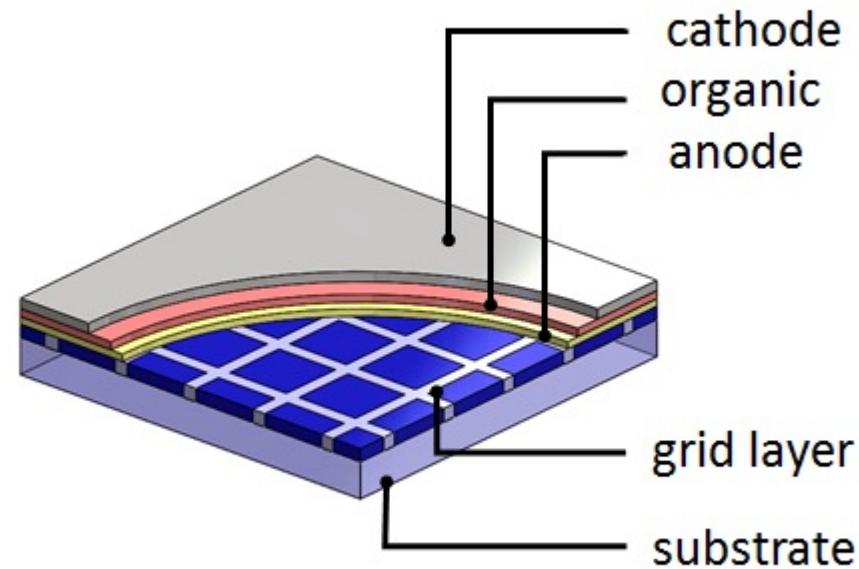


Method is Wavelength
Independent

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A better approach: Sub-Anode Grid

- ❑ A multi-wavelength scale dielectric grid between glass and transparent anode (sub-anode grid)
- ❑ The grid is removed from the OLED active region
- ❑ Waveguided light is scattered into substrate and air modes

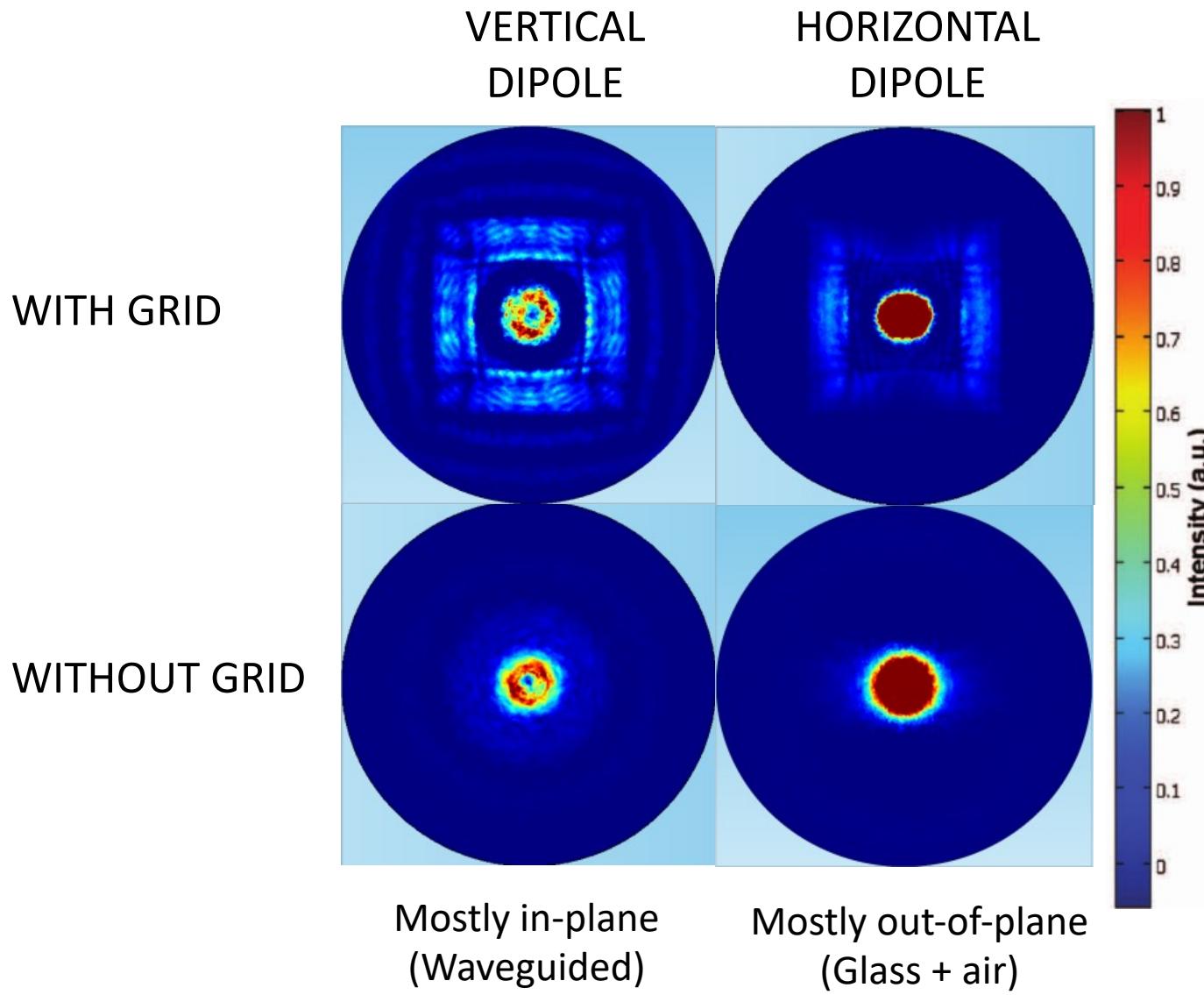


waveguided
power +
dissipation

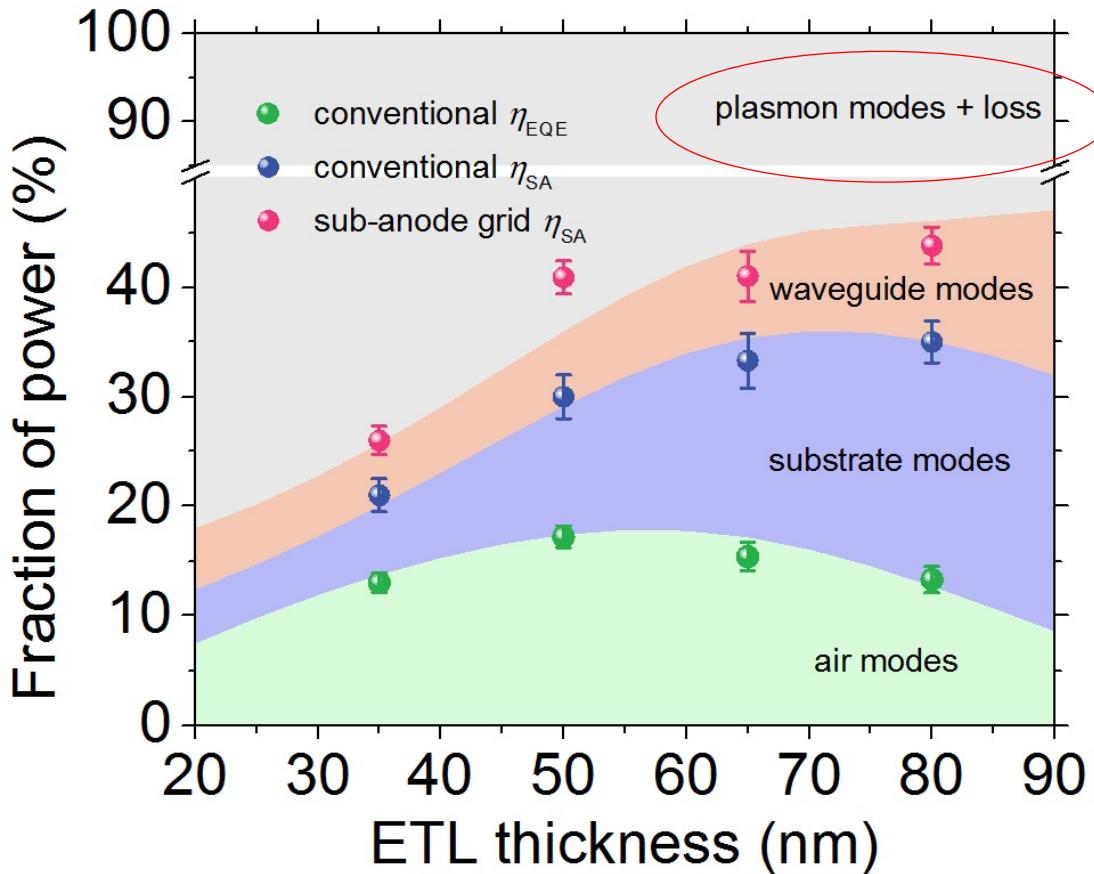
Collect substrate
mode power

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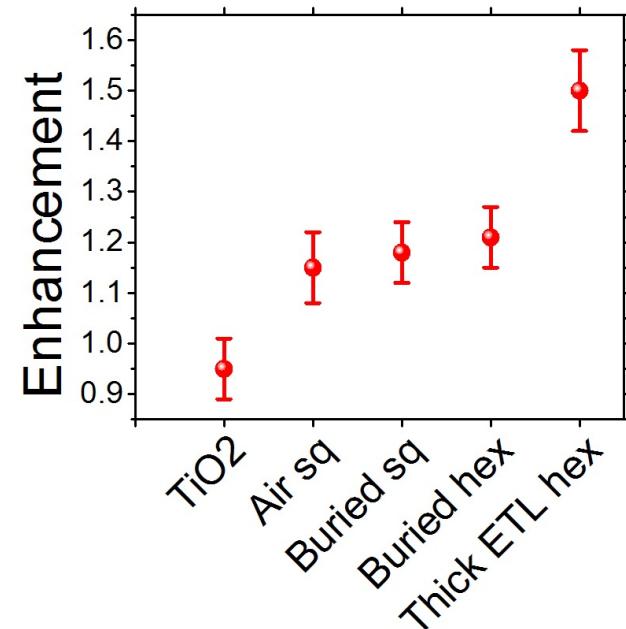
Emission field calculations



Optical Power Distribution



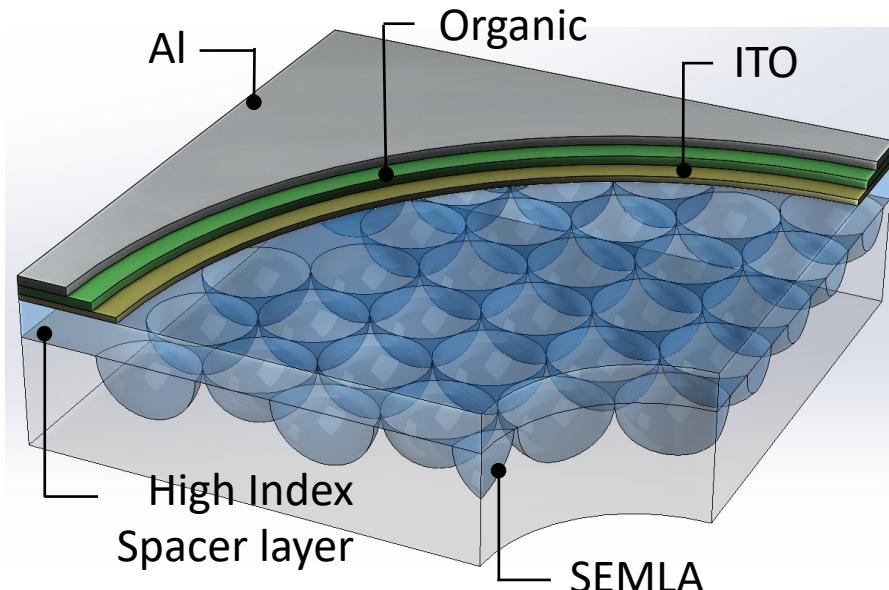
2nm MoO₃/40nm CBP/15nm CBP:Ir(ppy)₃/xnm
TPBi/1nm LiF/Al



Thick-ETL organic structure:

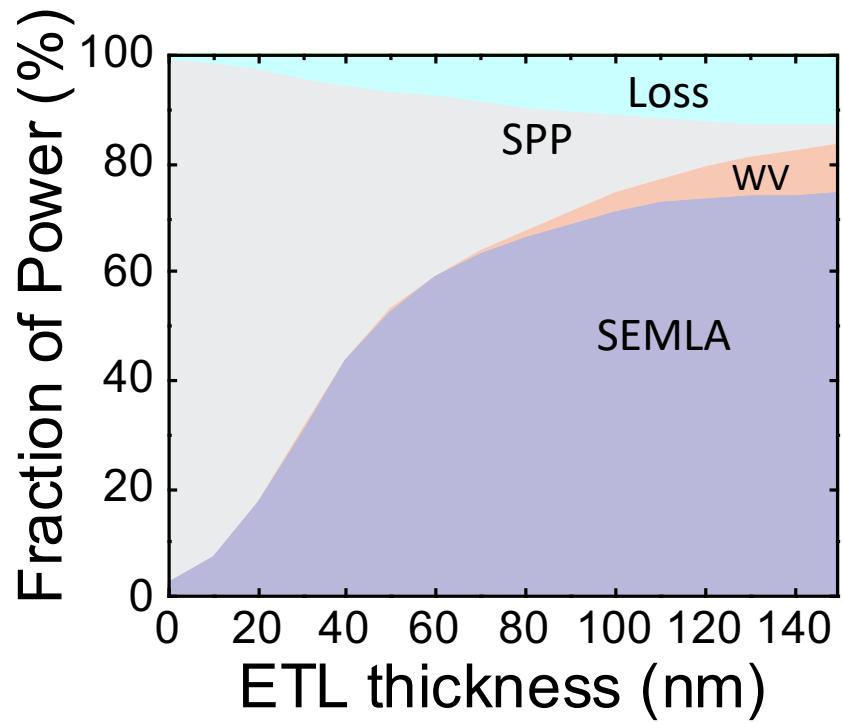
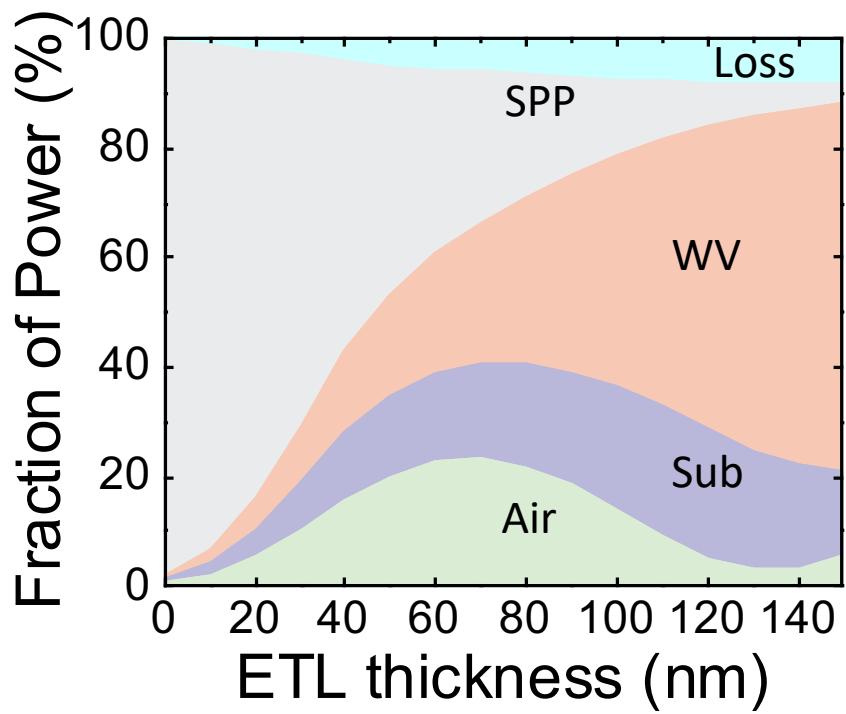
340nm grid/70nm ITO/2nm MoO₃/40nm
TcTa/15nm CBP: Ir(ppy)₃/10nm TPBi/230nm
Bphen:Li/Al

Getting All the Light Out: Sub-Electrode Microlens Array (SEMLA)

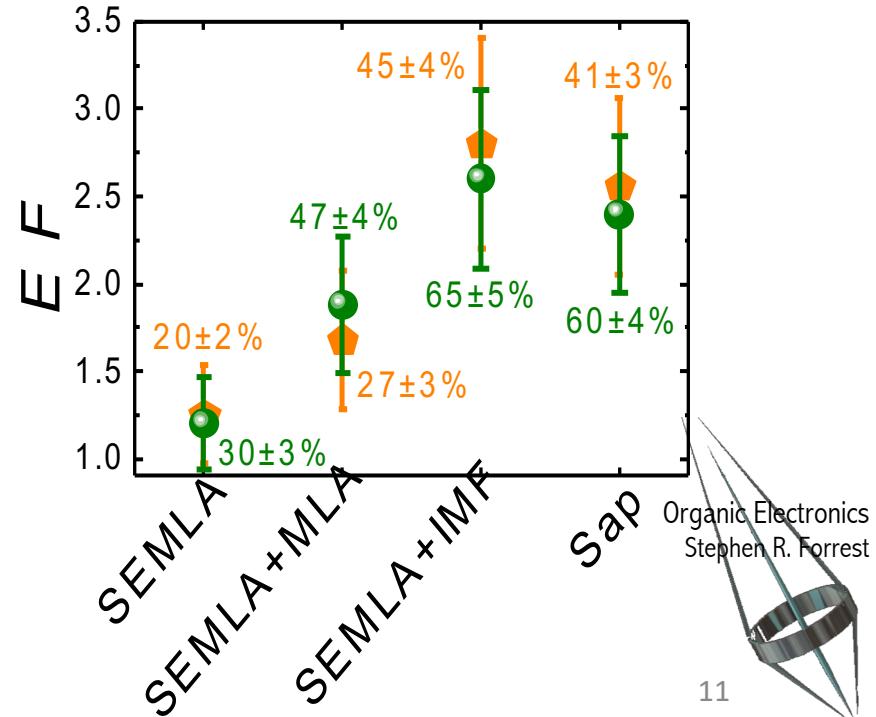
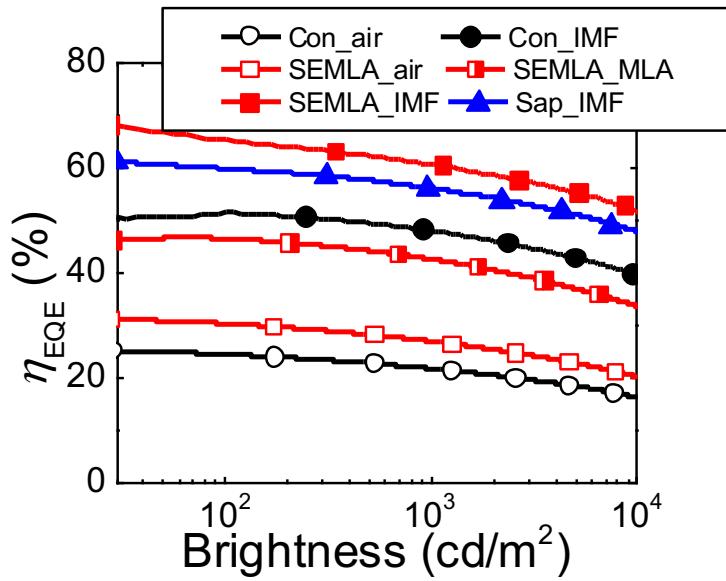
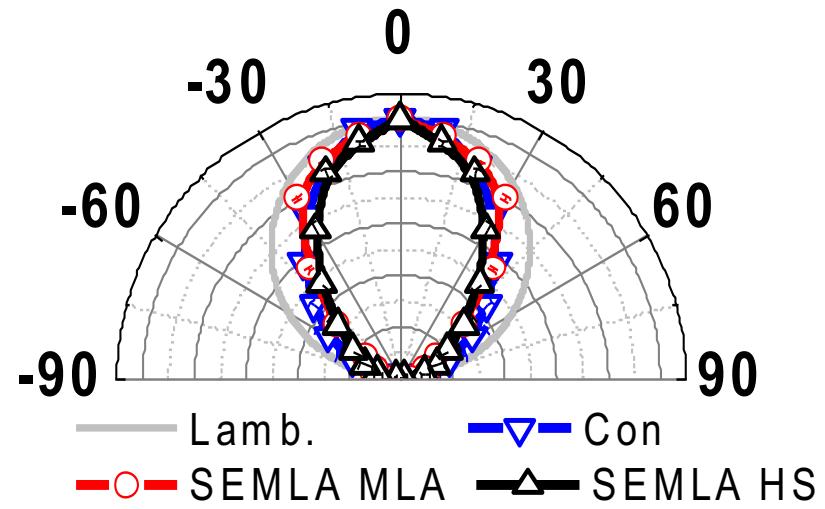
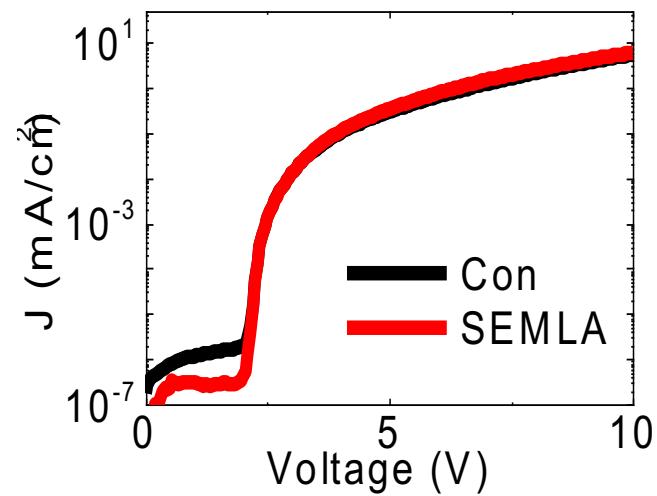


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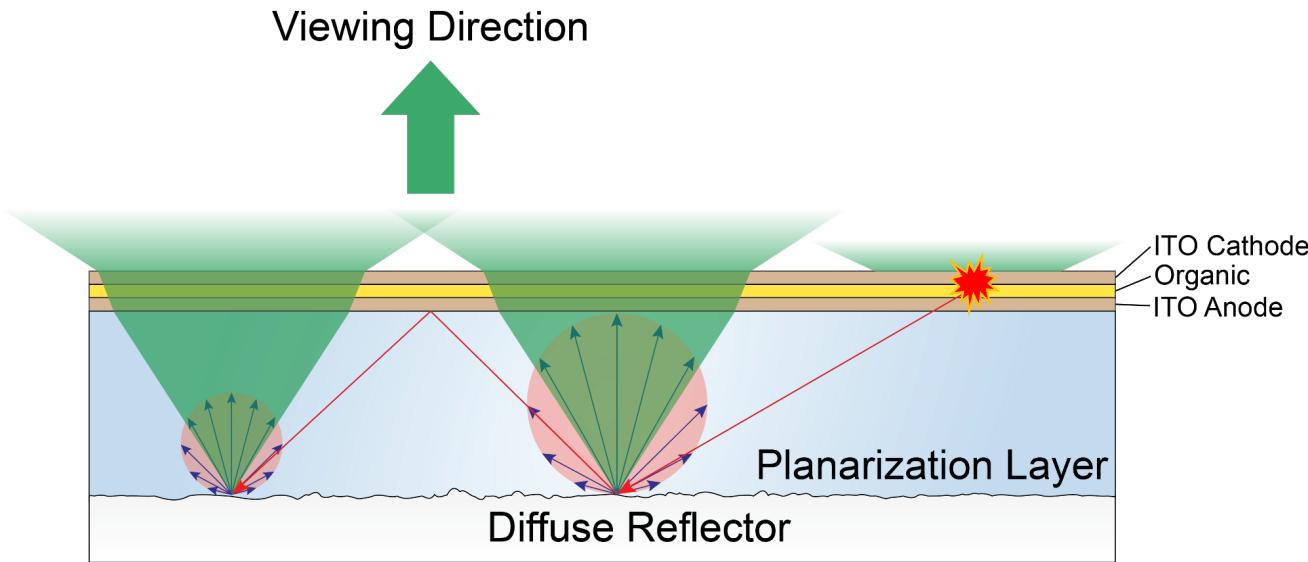
SEMLAs Change the Outcoupling Landscape



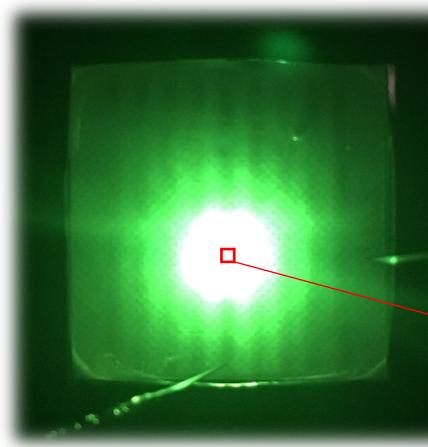
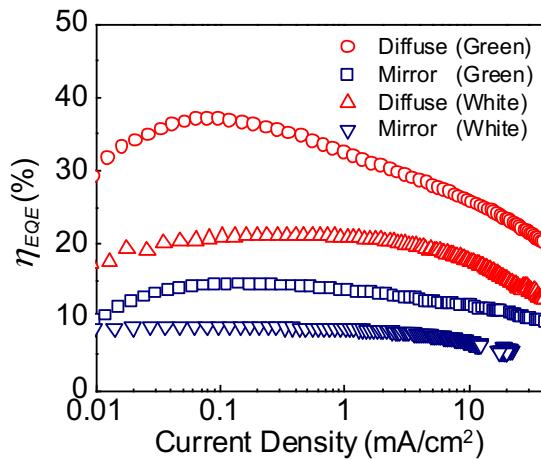
SEMLA Performance



Diffuse Reflectors: Low Cost & Simple



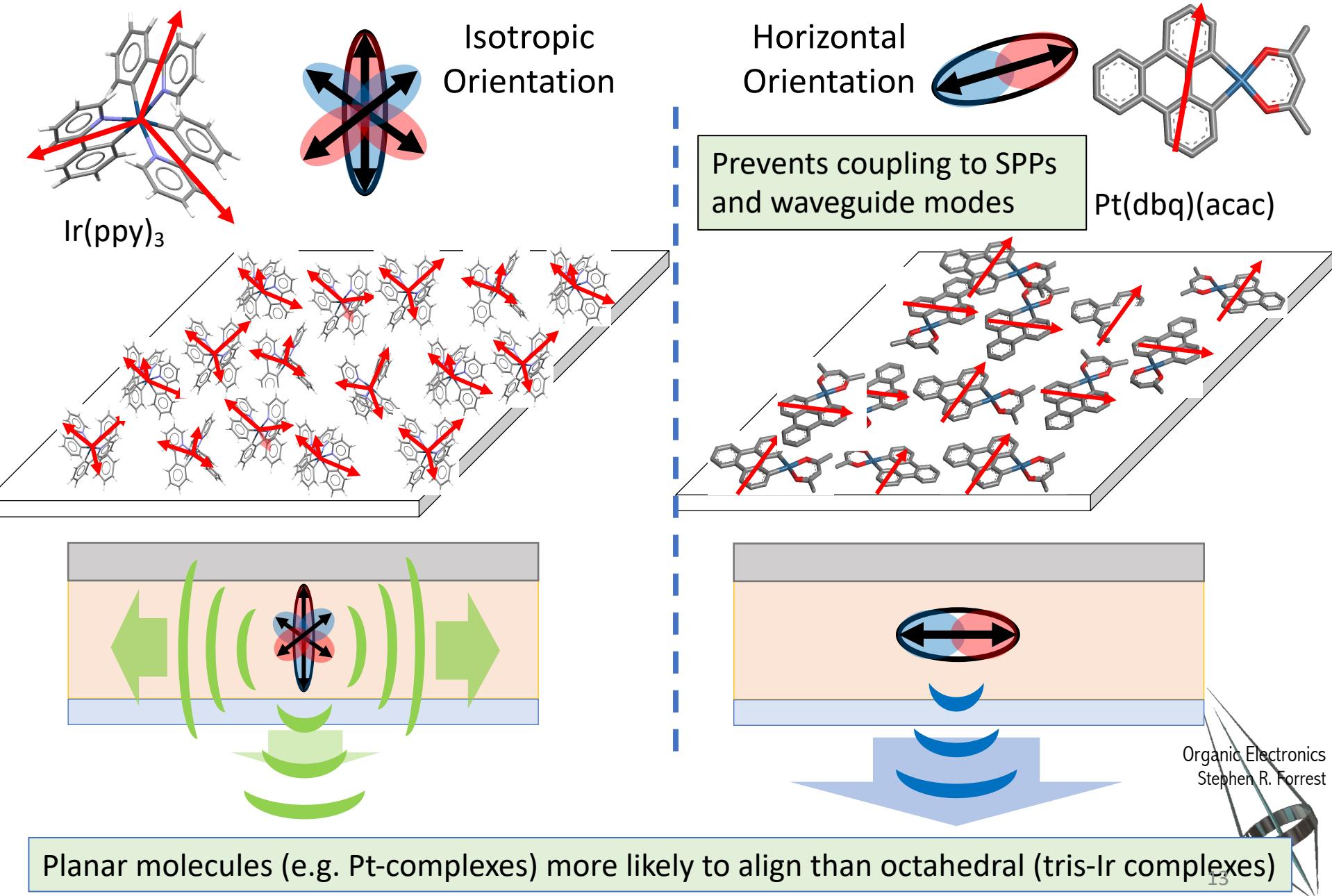
Teflon is the best diffuse dielectric reflector



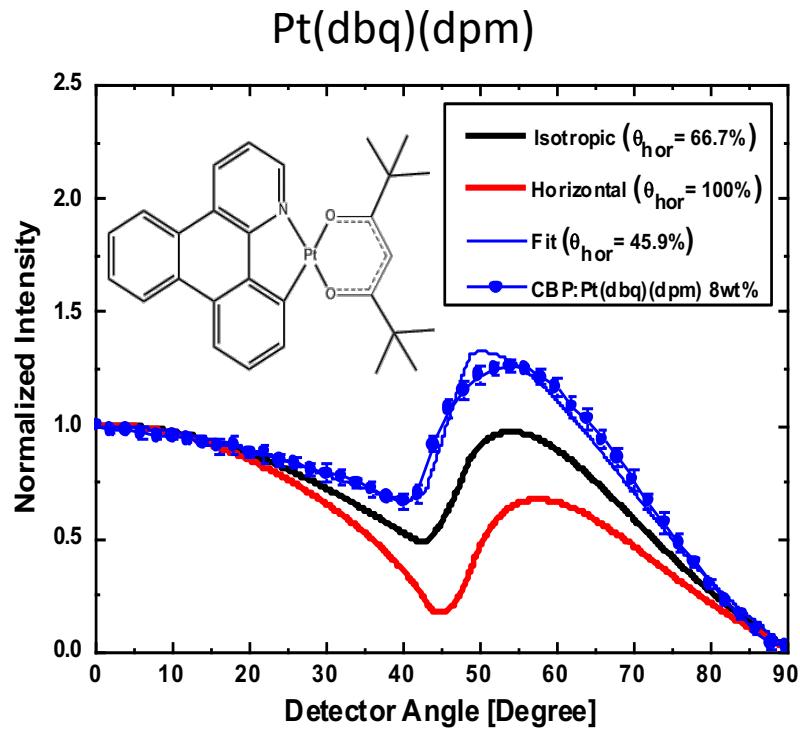
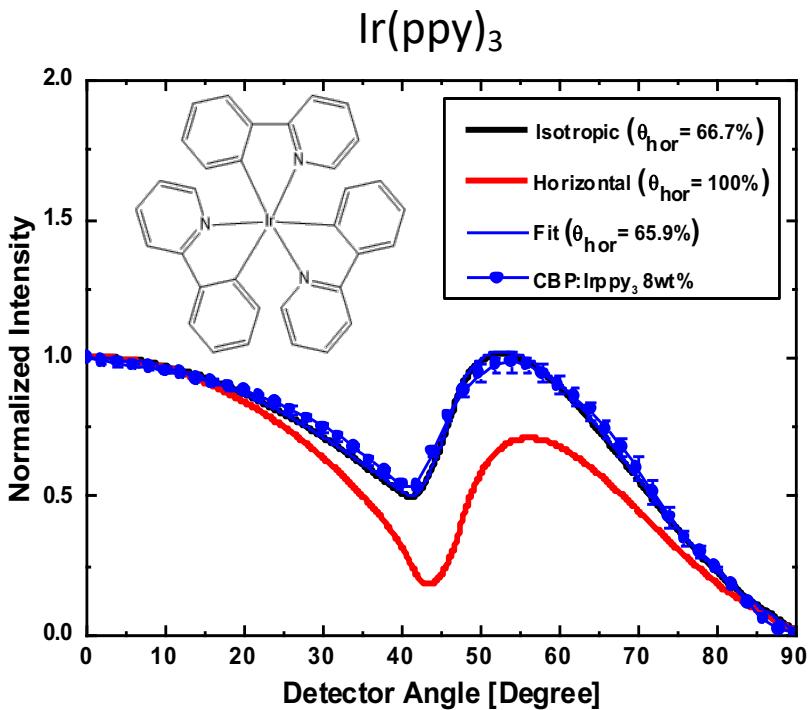
PHOLED
Active Area

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Outcoupling Enhancements by Molecular Orientation



Example results



Ratio of light emitting by vertical to horizontal dipoles: $\Theta = \frac{TM_{||}}{TE_{\perp} + TM_{\perp} + TM_{||}}$

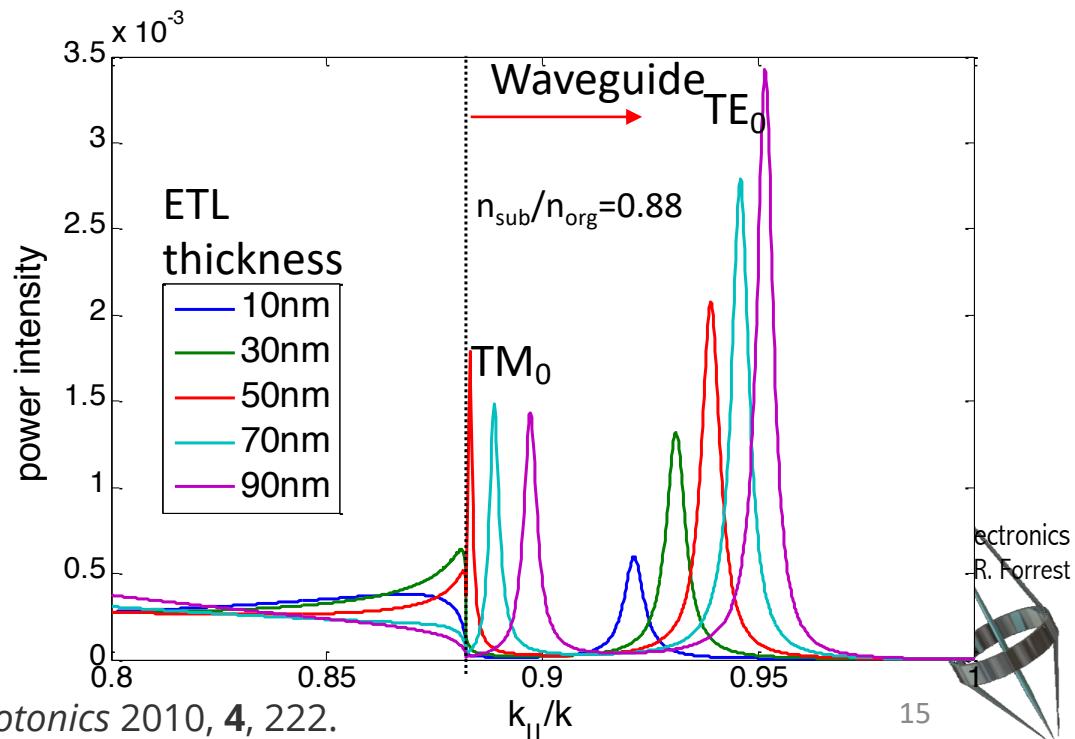
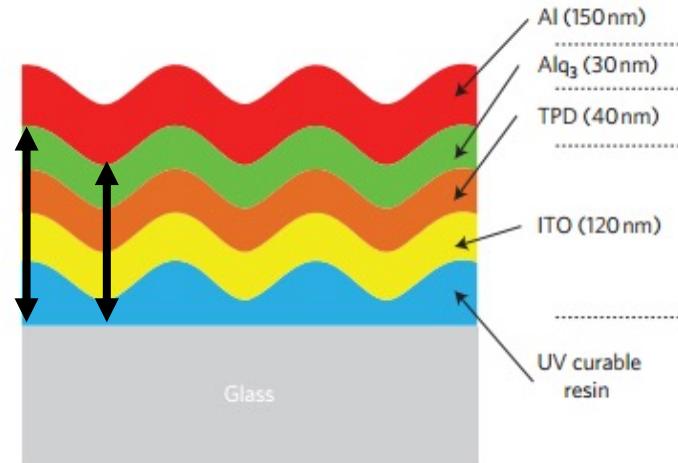
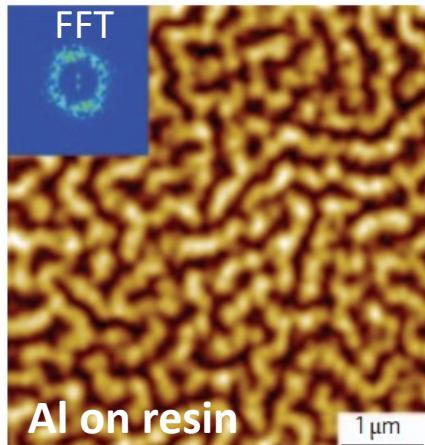
Approach challenges

- Added constraints on molecular design
- Added constraints on process (growth) conditions: may not align as expected
- Added constraints on device architecture
- Alignment is never “perfect”: only modest improvements

Substrate Corrugations Can Outcouple Waveguide Modes

- Waveguide thickness varies due to the corrugation.
- As the thickness changes, the mode distribution changes.
- When the waveguided power travels from thin to thick areas, the k vector needs to change direction to keep “being trapped”. Otherwise, the light is extracted.

A possible approach: Surface buckling?



Reliability Testing Methodologies

- Need to set clear metrics for failure
 - Example: Operating time for initial luminance (L_0) to decrease 10% from its initial value (called T90, or LT90)
 - Employ a population of equivalent devices and monitor their performance parameter (e.g. luminance) under normal operating conditions
 - If degradation slow, then an empirical degradation relationship is determined to extrapolate time to failure
 - Example: **Stretched exponential function:**
$$L(t) = L_0 \exp(-t/\tau)^\beta \quad \tau, \beta = \text{empirical constants}$$
 - If degradation too slow, need to accelerate via increased T or L_0 .
 - Accelerated conditions must not introduce new failure modes
 - Need empirical relations to normalize lifetime to standard operating conditions (called **acceleration factors**)

$$LTx(L_0) = LTx(L_{0tst}) \cdot \left[\frac{L_{0tst}}{L_0} \right]^n \quad n = \text{empirical acceleration factor}$$

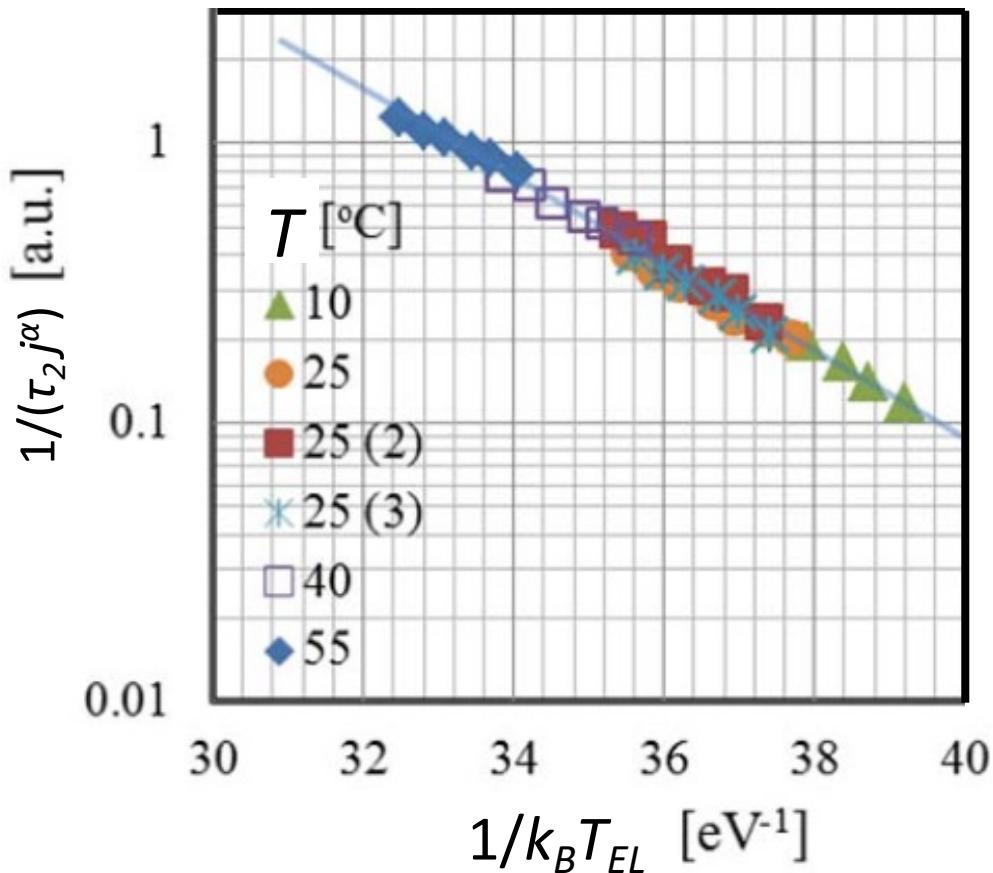
Accelerated Degradation Methodologies

Sum of lifetimes alternative empirical relation):

$$L(t)/L_0 = \lambda \exp(-t/\tau_1) + (1-\lambda) \exp(-t/\tau_2)$$

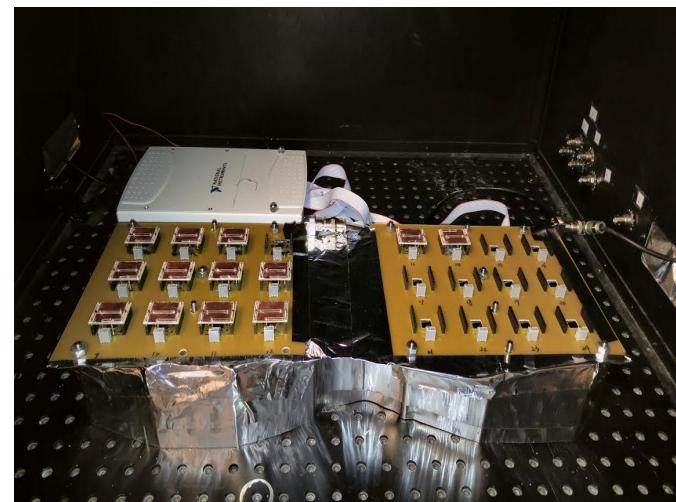
Burn-in Long term decay

Example data: Green PHOLED



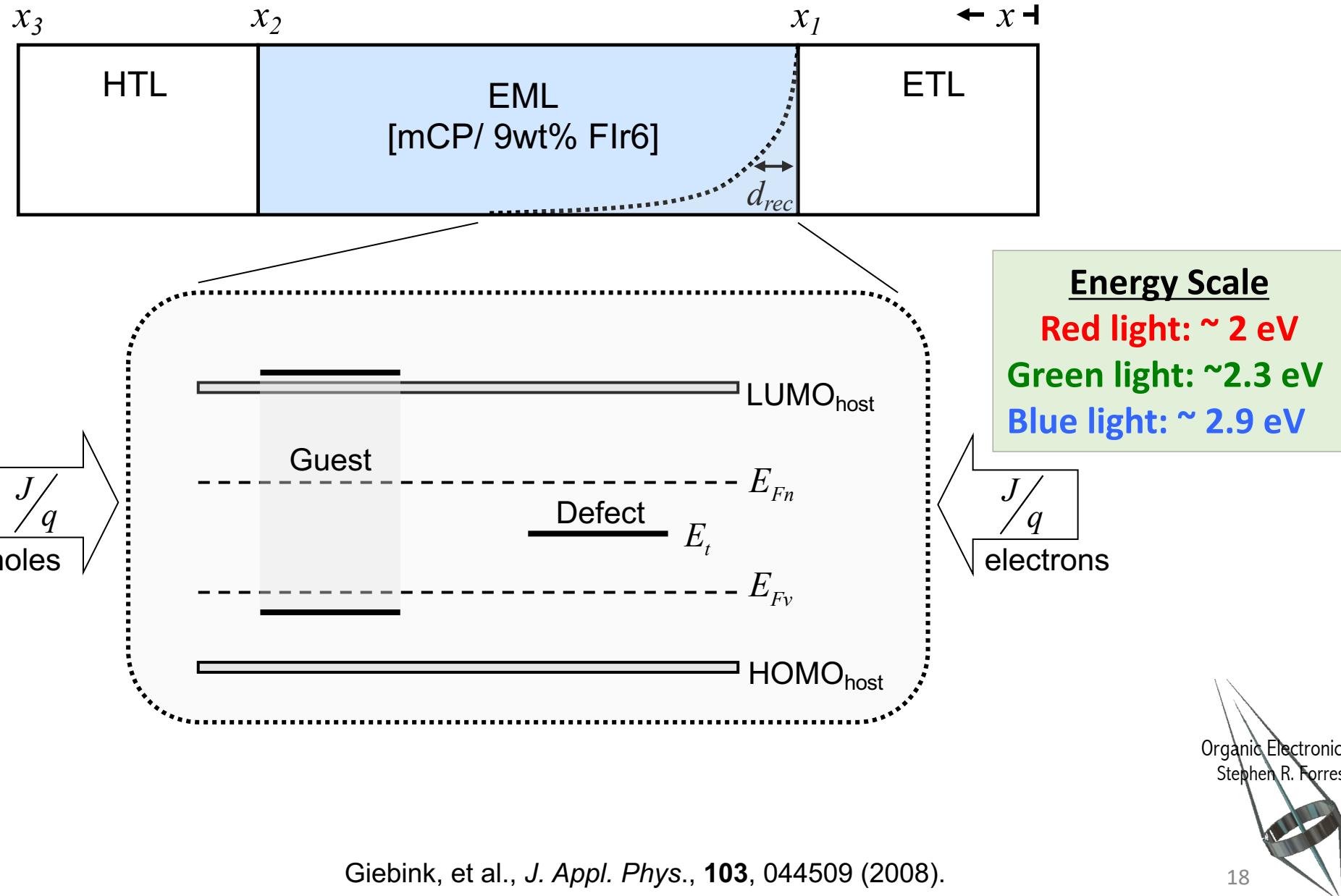
$$\frac{1}{\tau_2} = K'' j^\alpha \exp(-\Delta E_{A0}/k_B T)$$

ΔE_{A0} =thermal activation of degradation
 α = current acceleration factor



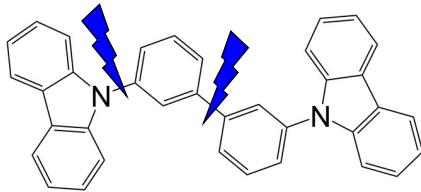
Measuring populations of identical devices

Intrinsic Lifetime Limits of OLEDs



Degradation Routes

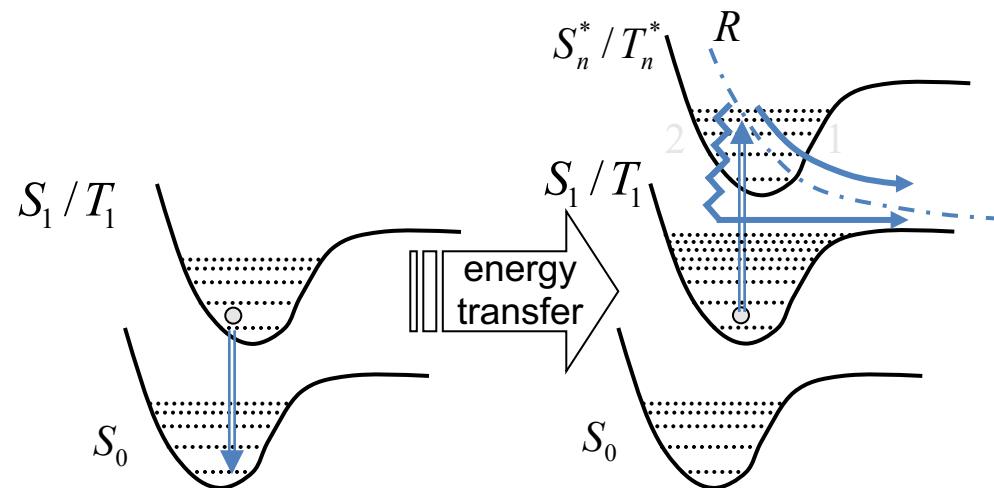
- Energetically Driven
 - Lifetime: $R > G > B$
- Two particle interactions lead to luminance loss
 - Exciton on phosphor, polaron on host
 - Exciton-exciton also possible



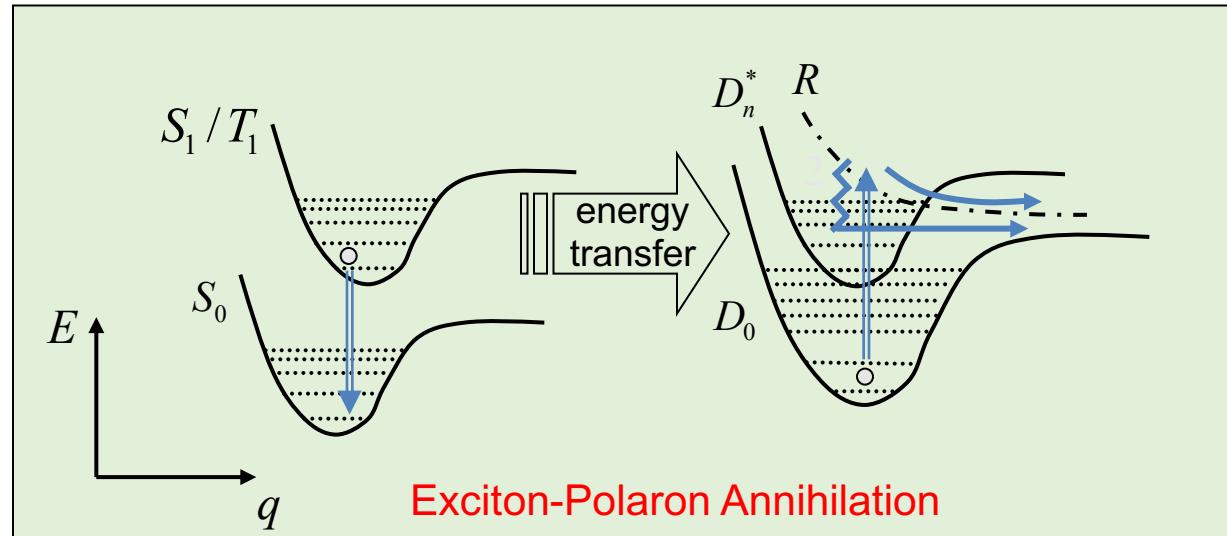
Bond	BE(eV)	Bond	BE(eV)
C-C	3.64	N-N	1.69
C-H	4.28	N-O	2.08
C-O	3.71	N-H	4.05
C-N	3.04	O-O	1.51
C-F	5.03	H-H	4.52

Bond cleavage

Broken bonds? \rightarrow Defects!



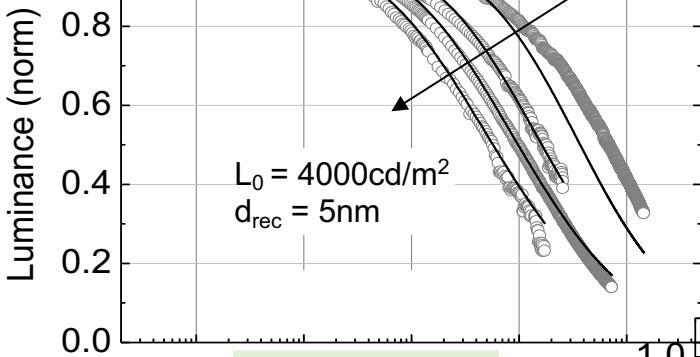
Exciton-Exciton Annihilation



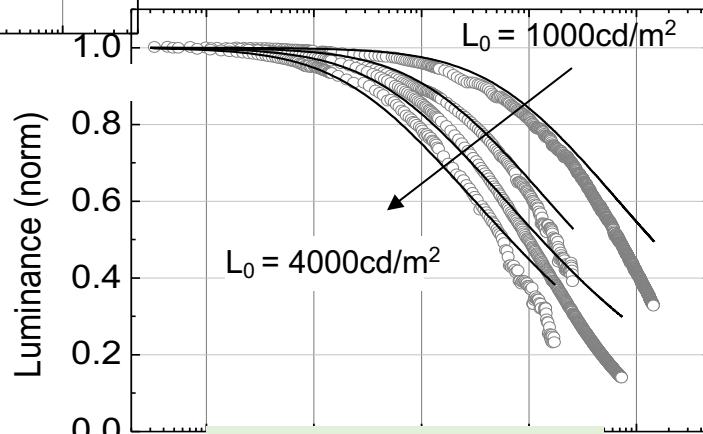
Exciton-Polaron Annihilation

Triplet energy (~2.8 eV) + polaron (~3.3 eV) = hot polaron (≥ 6 eV)

Luminance Decay vs Time



Exciton
Localization

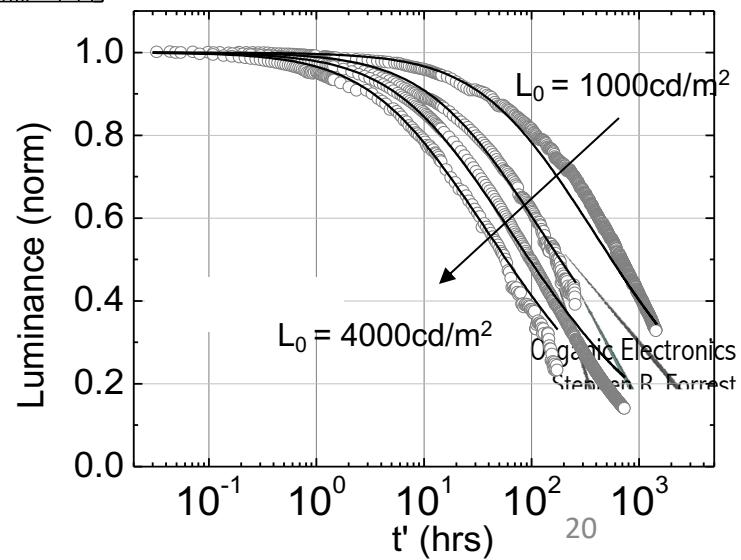


Exciton-Exciton
Annihilation

Defect Generation Rates

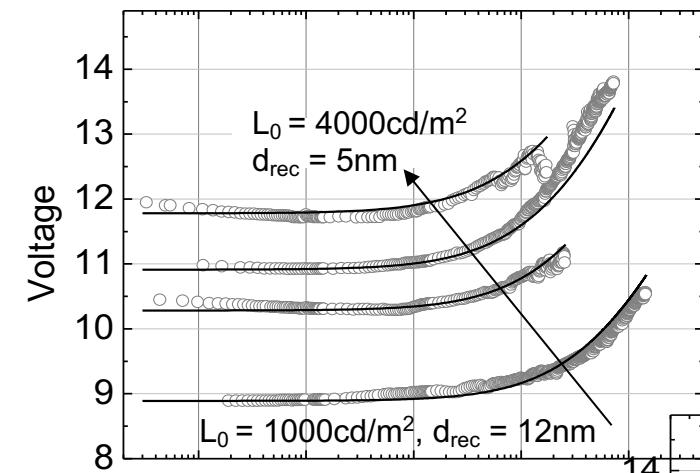
$$\frac{dQ(x,t')}{dt'} = \begin{cases} K_X n(x,t') & K_X p(x,t') \\ K_X N(x,t') & \text{P} \\ K_X N^2(x,t') & \text{E} \\ K_X N(x,t')n(x,t') & \text{E-E} \\ & K_X N(x,t')p(x,t') \end{cases}$$

P
E
E-E
E-P

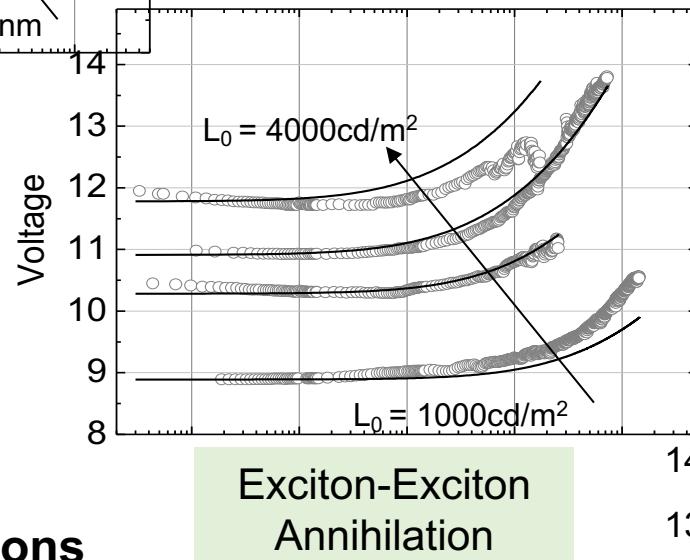


Exciton-Polaron
Annihilation

Drive Voltage Drift with Aging



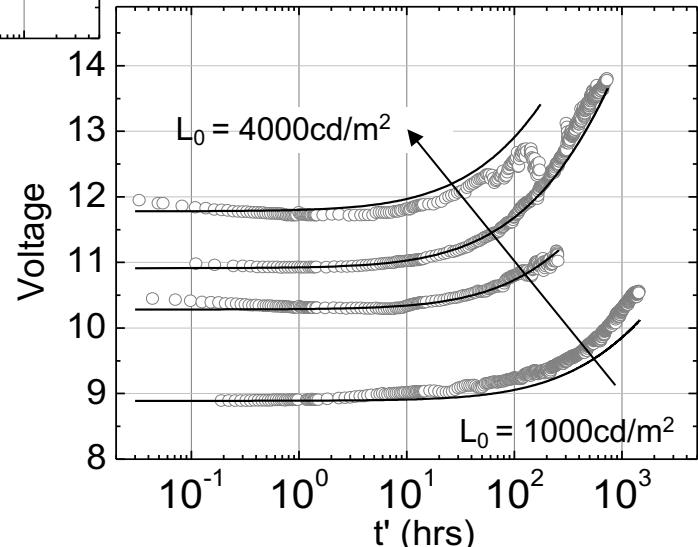
Exciton
Localization



Exciton-Exciton
Annihilation

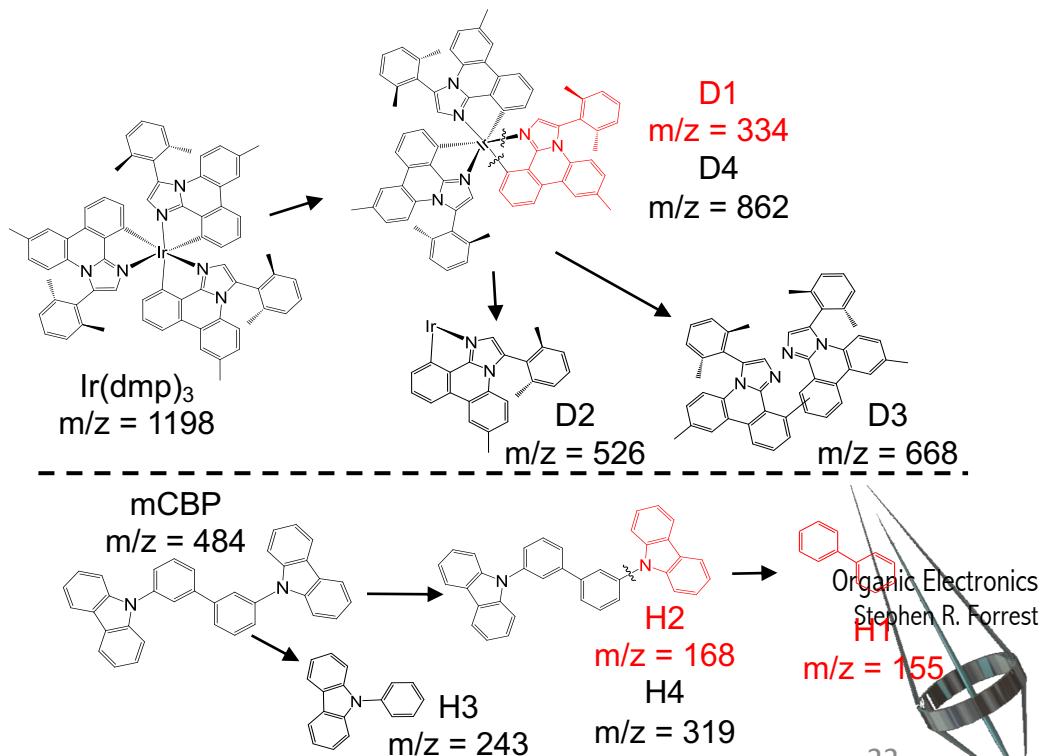
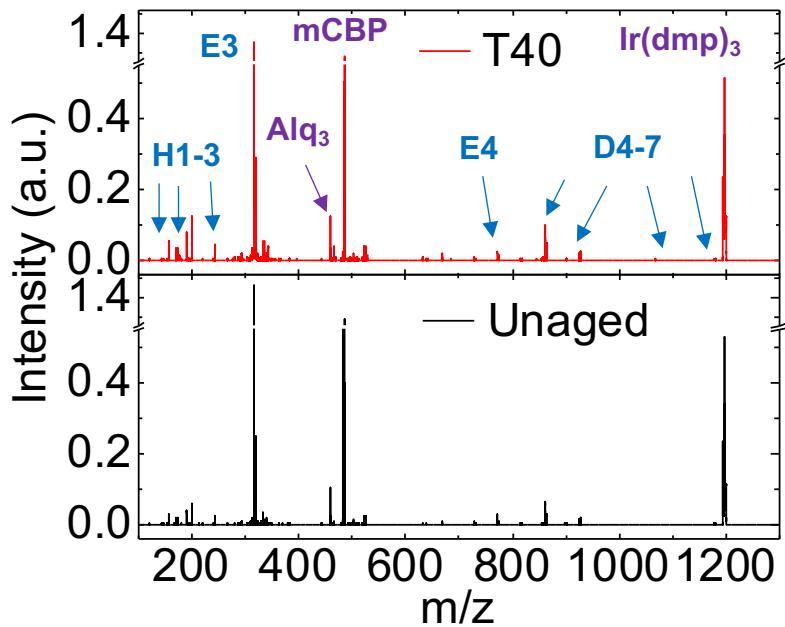
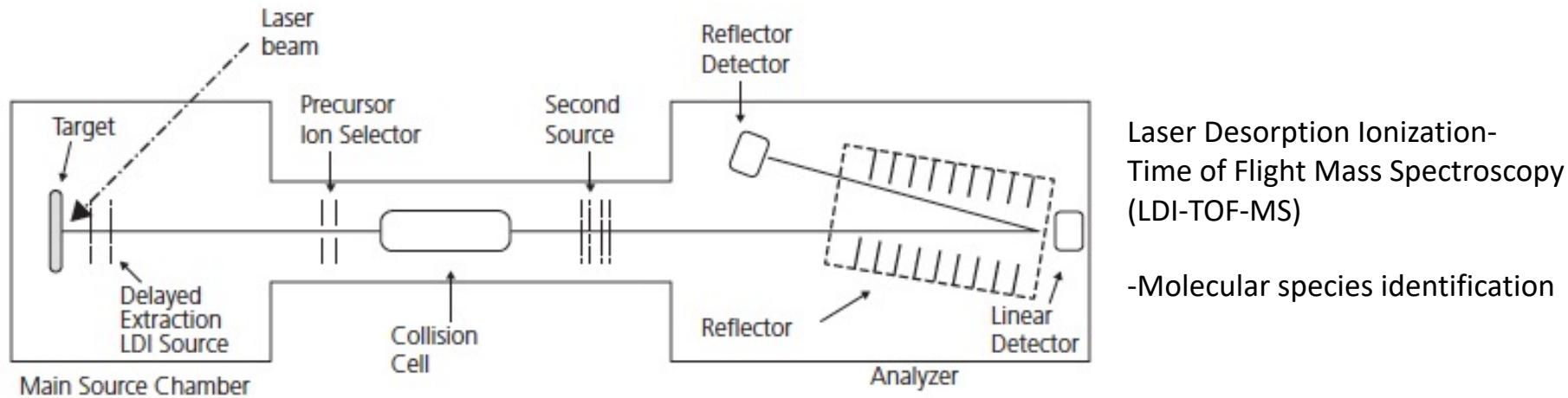
Conclusions

- $\bullet Q \sim 10^{18} \text{ cm}^{-3} \rightarrow 50\% \text{ increase in quenching}$
- $\bullet \text{At } 1000 \text{ cd/m}^2, \text{ formation rate} = 10^{12} \text{ cm}^{-2} \text{s}^{-1}$
 - 1 in 5×10^8 E-P encounters leads to defect
 - Increasing recombination zone width extends lifetime
 - Guest triplets/host polarons most active

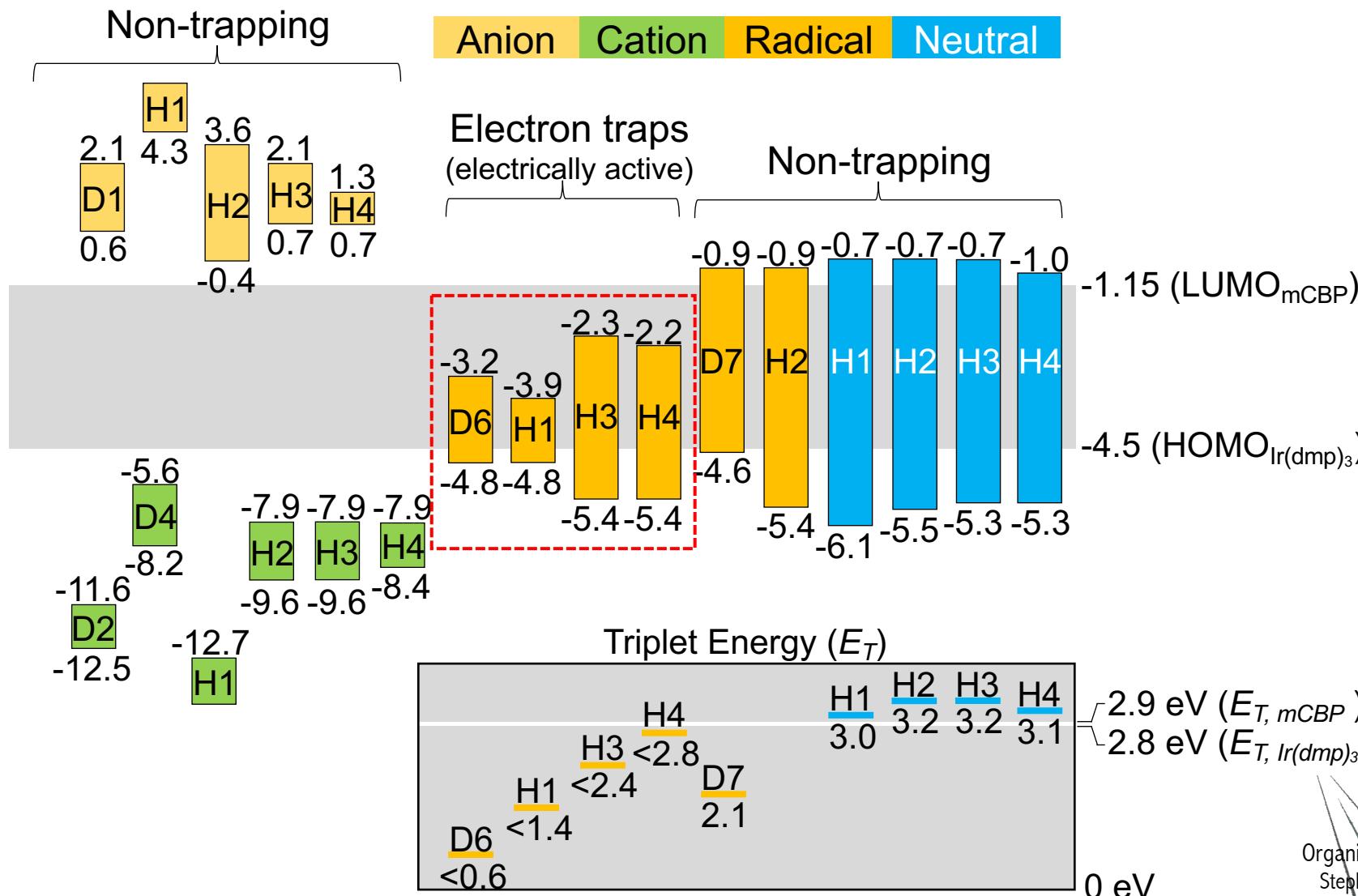


Exciton-Polaron
Annihilation

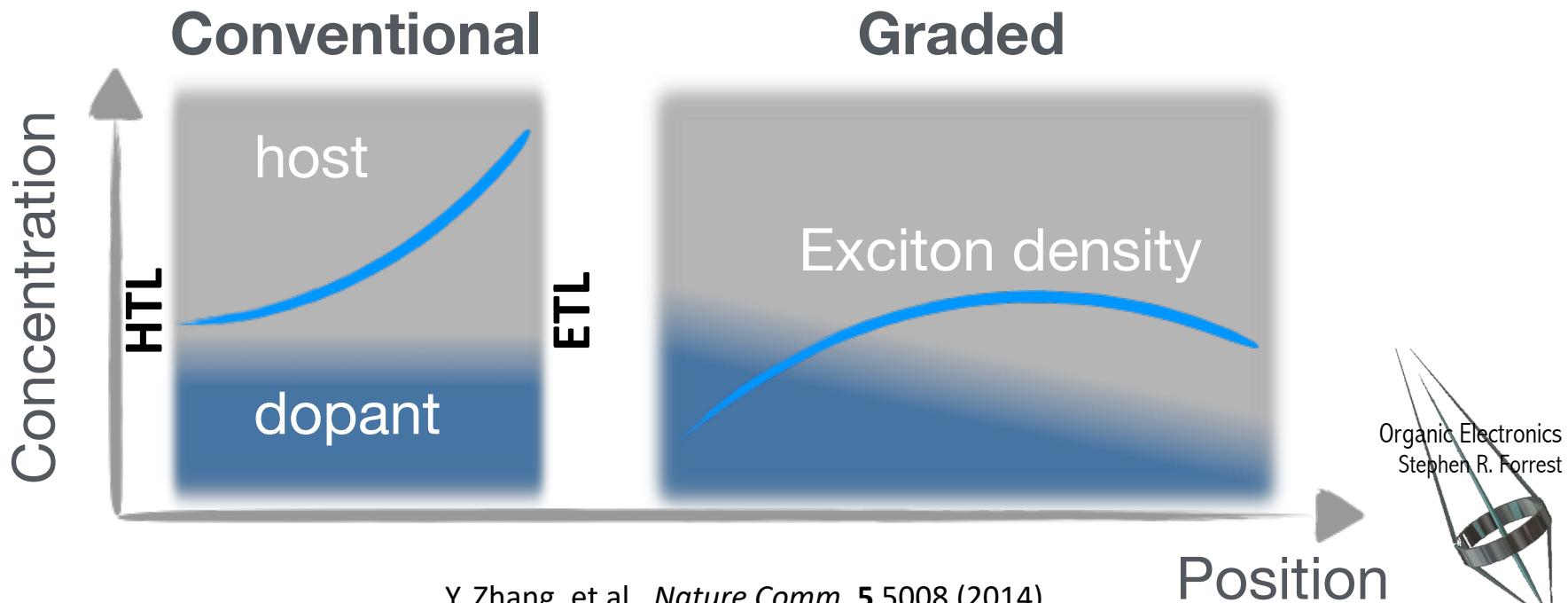
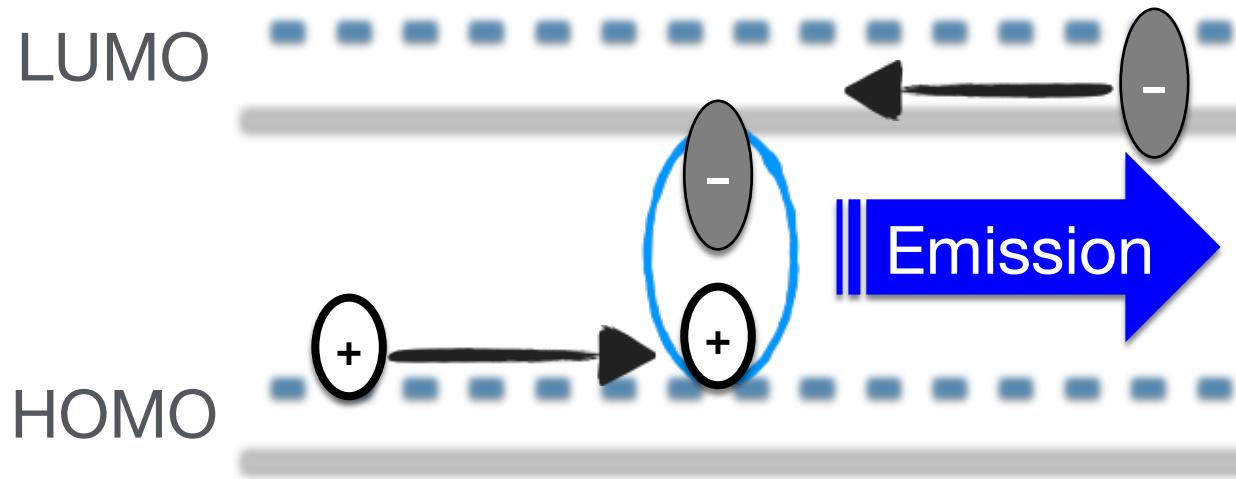
Evidence for Defect Formation: Molecular Fragmentation



Identification of Defect Energies

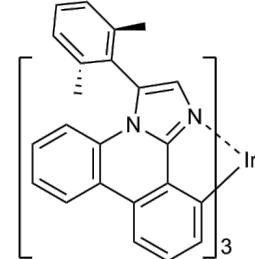
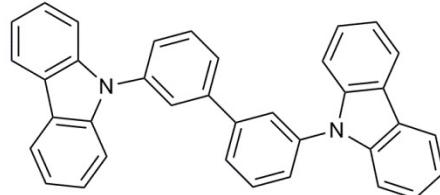


Reducing Exciton Density to Increase Lifetime



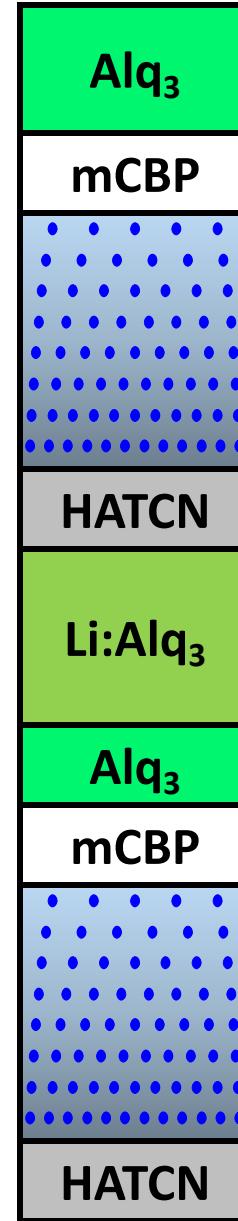
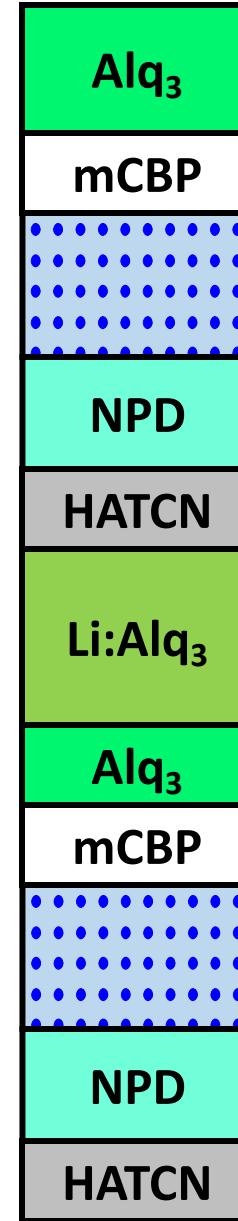
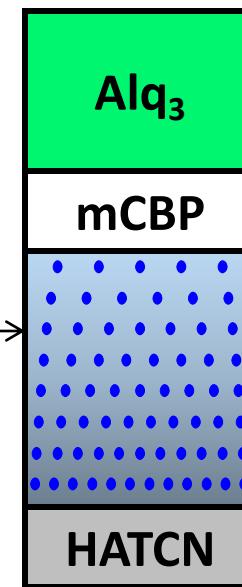
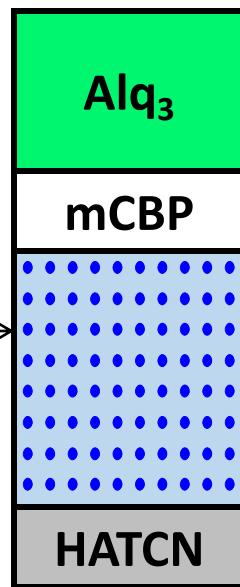
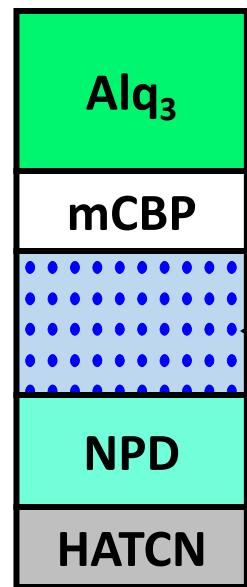
Spreading the recombination zone: Dopant/Host Grading

3 Different test device structures

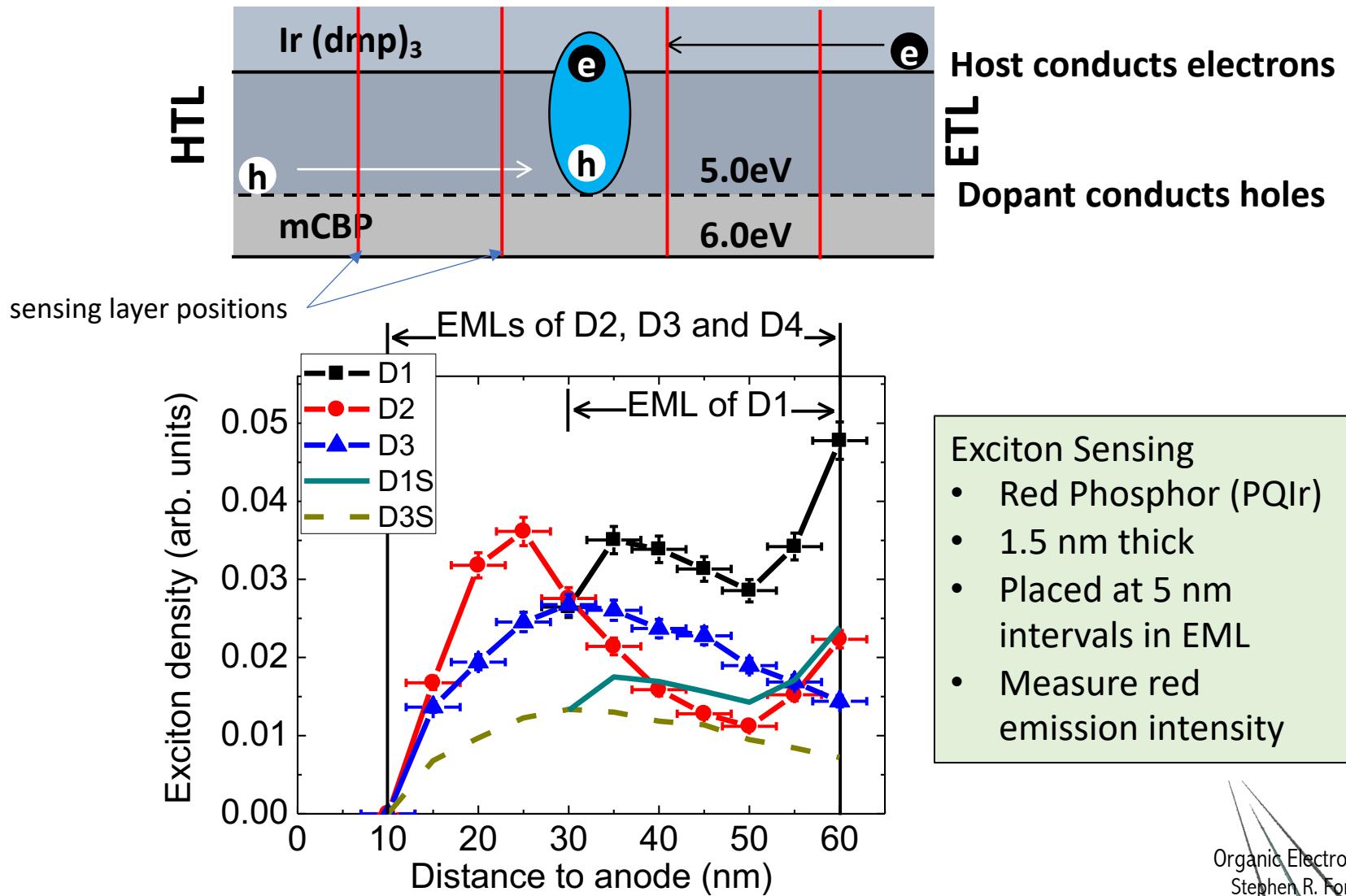


13 vol% uniform

8 to 18% vol% graded



Excitons in the EML



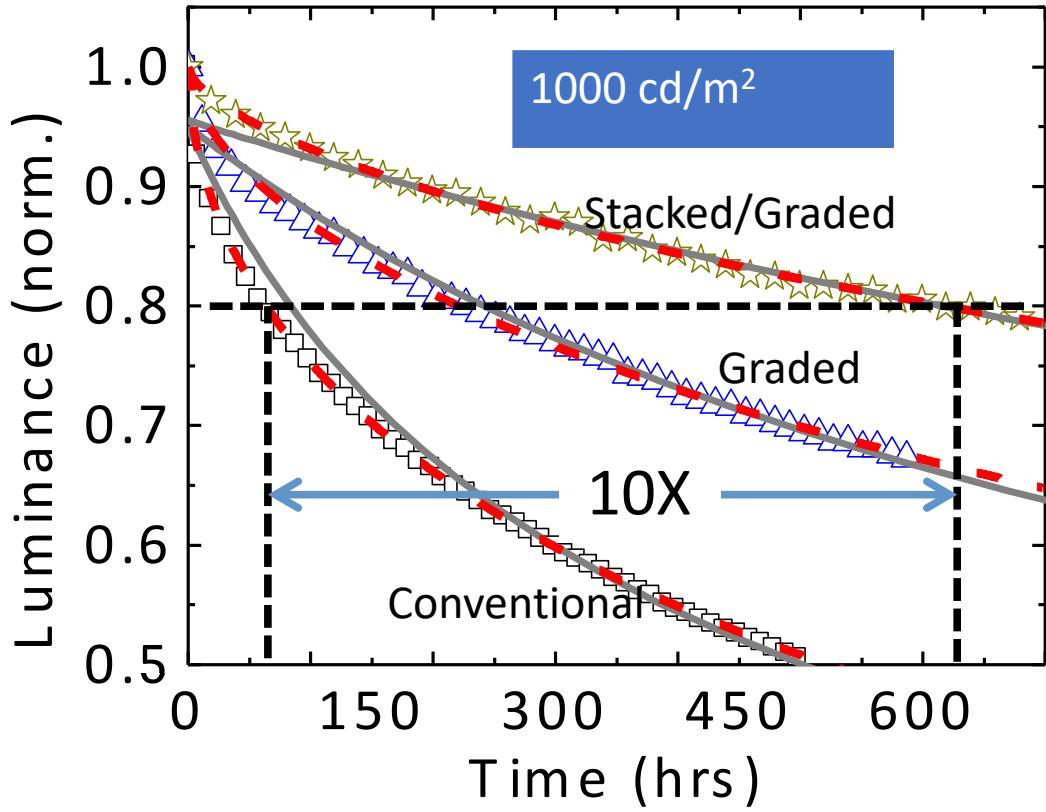
Host conducts electrons
Dopant conducts holes

Exciton Sensing

- Red Phosphor (PQIr)
- 1.5 nm thick
- Placed at 5 nm intervals in EML
- Measure red emission intensity



10 X Lifetime Improvement Over Conventional



Stacking is essential!



Panel 15 cm x 15 cm 82% fill factor	2 Unit WSOLED
Luminance [cd/m ²]	3,000
Efficacy [lm/W]	48
CRI	86
Luminous Emittance [lm/m ²]	7,740
1931 CIE	(0.454, 0.426)
LT ₇₀ [hrs]	13,000

Dopant Grading: Is it Good Enough?

using acceleration factors to predict lifetime

- Luminance to achieve sRGB color gamut for G is 10X that for B
- \Rightarrow B sub-pixel $L_0 = 100 \text{ cd/m}^2$ (c.f. G with $L_0 > 1,000 \text{ cd/m}^2$)
- \Rightarrow B lifetime to T50 = 70,000 hr.
- Adopting Degradation acceleration factor: $n = 1.55$ with

$$T50(100\text{cd/m}^2) = T50(1000\text{cd/m}^2) \times \left[\frac{1000\text{cd/m}^2}{100\text{cd/m}^2} \right]^n$$

- \Rightarrow B PHOLED lifetime to T50 = 1.3×10^5 hr.
- Commercial G PHOLED lifetime = 10^6 hours at $L_0 = 1000 \text{ cd/m}^2$.

Not blue enough, T95 is required

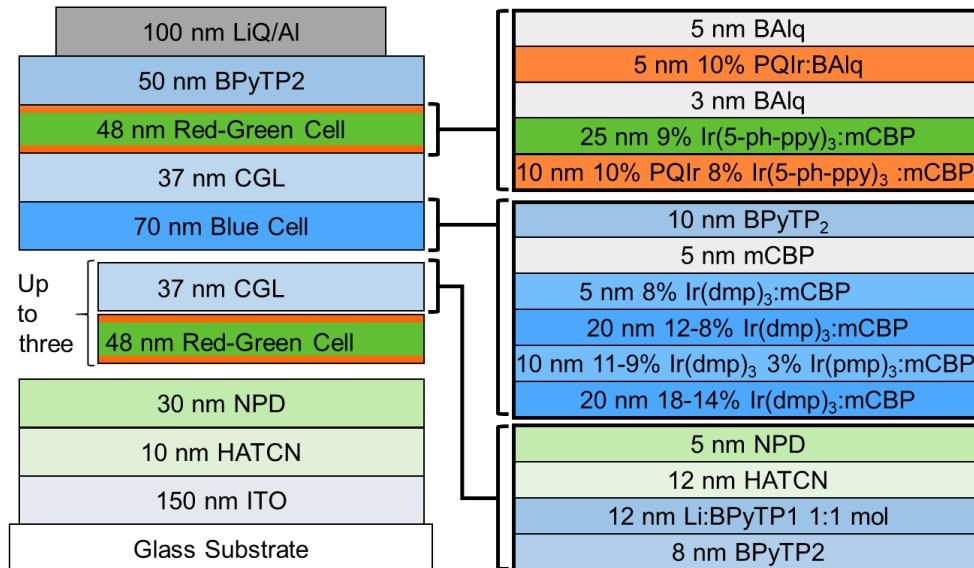
Dopant Grading for Lighting: Is it OK?

- Current state of stacked WOLED: $T_{70}=13,000$ hrs
- Mostly limited by blue lifetime
- Only light blue required
- Estimated increase in lifetime for stacked blue at lighting brightness: $\sim 4X$
- Lifetime of blue lighting using grading: 50,000 hr

This is almost good enough

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Putting Grading Excited State Management to Work: Long lived all phosphor stacked WOLEDs

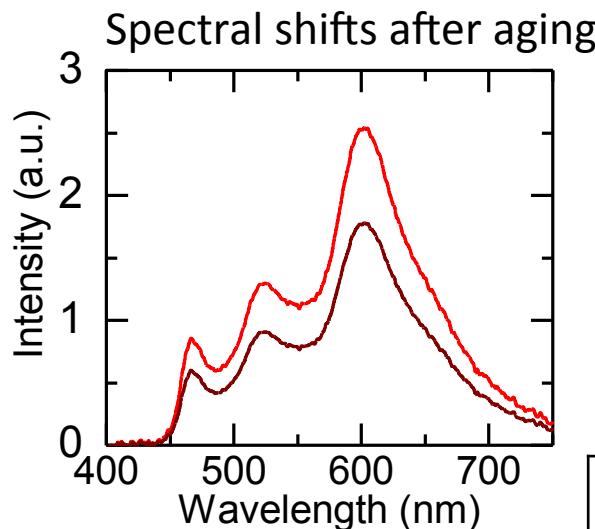
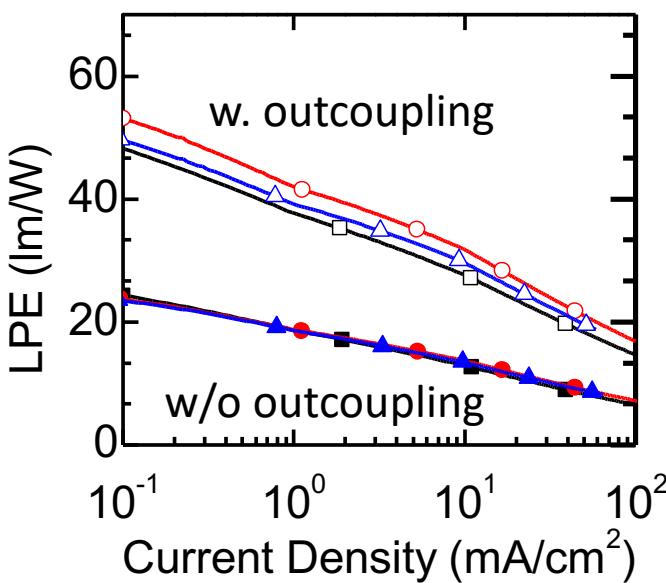


- Max Luminance > 200,000 nits
- 50 lm/W max
- CCT = 2780K
- CRI=89

Photo illustrating good color rendering of the SWOLEDs in this report. The luminaire comprises 36 pixels (2 mm^2) operated at 50-100k nits

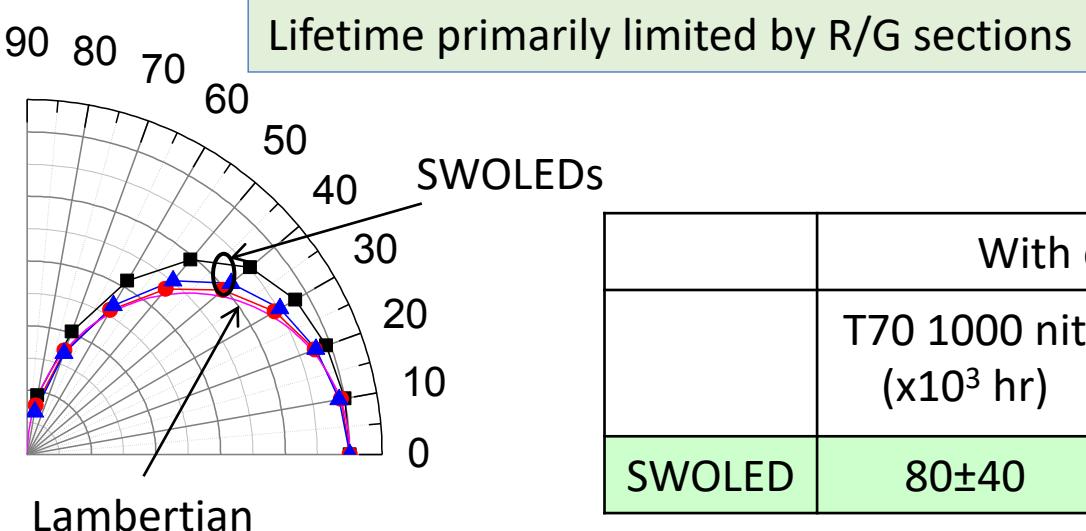
Electronics
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All Phosphor SWOLED Performance

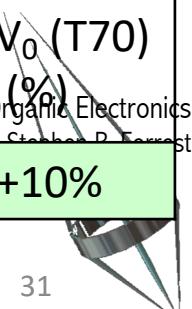


T70	SWOLED
ΔCCT	-360 K
ΔCRI	-0.8
ΔCIE	(0.03, 0)

SWOLED Architecture	Blue degradation @ WOLED T70:
Conv	T28
Grad-Managed	T48



	With outcoupling		$\Delta V/V_0$ (T70) (%)
	T70 1000 nit ($\times 10^3$ hr)	T70 3000 nit ($\times 10^3$ hr)	
SWOLED	80 ± 40	14 ± 5	$\sim +10\%$



What we learned about OLEDs

- Chromaticity and the perception of color is quantified based on eye response (photometric quantities)
- OLEDs reach highest efficiency when both singlets and triplets are harvested (heavy metal complexes and TADF molecules)
- Optimized OLEDs have many layers serving purposes ranging from charge conduction, contacting to electrodes, to light emission
- Outcoupling methods essential to view substrate and waveguide modes while limiting surface plasmons
- Degradation of OLEDs particularly severe for blue due to bimolecular annihilation
- Lighting requires broad spectral emission using multilayer devices or excimer emission
- OLEDs provide uniform, area lighting vs. specular LED lighting